



**Hewlett Packard  
Enterprise**

# **Integrated Photonic Interconnect Reliability for Datacom Applications**

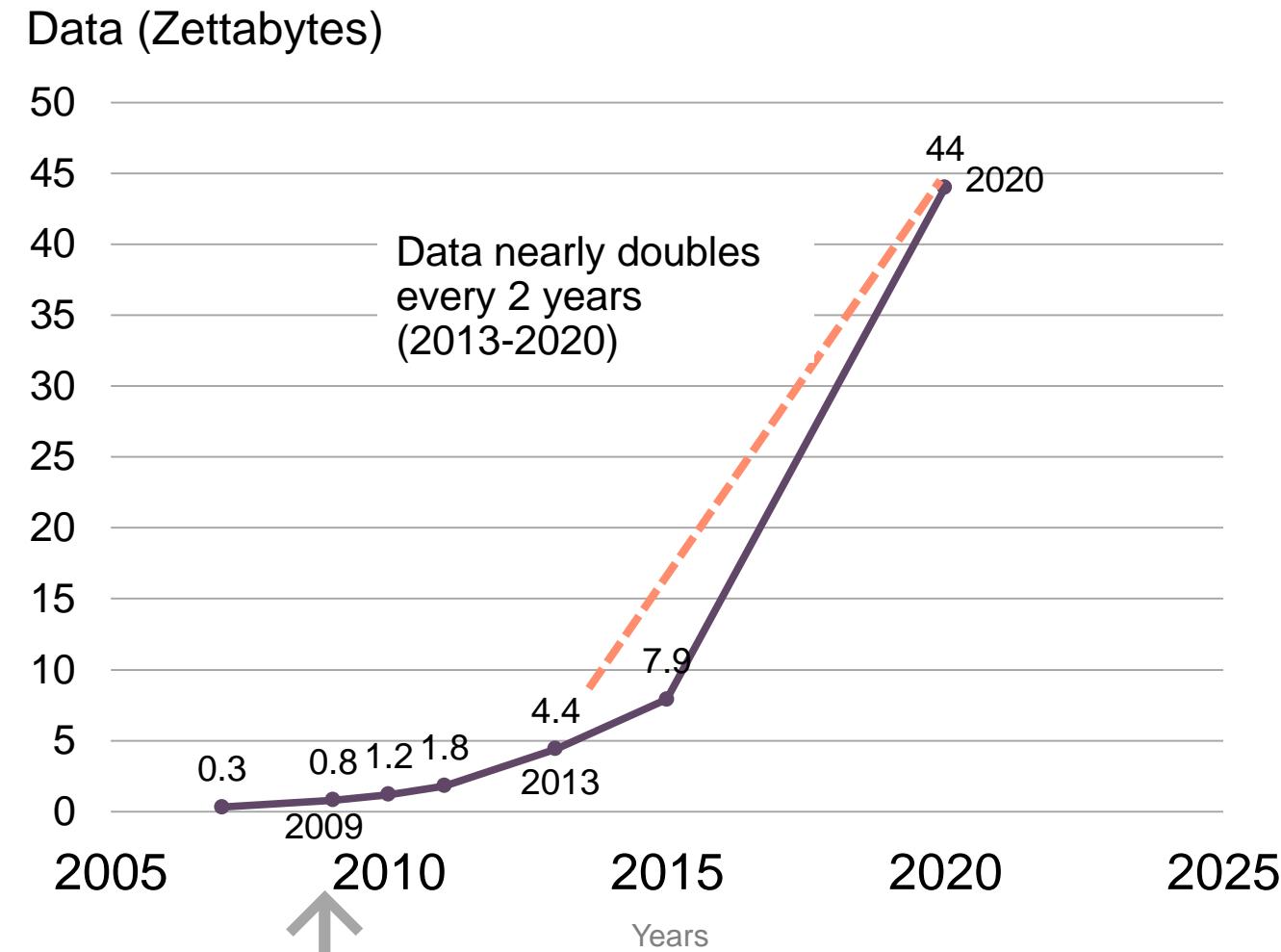
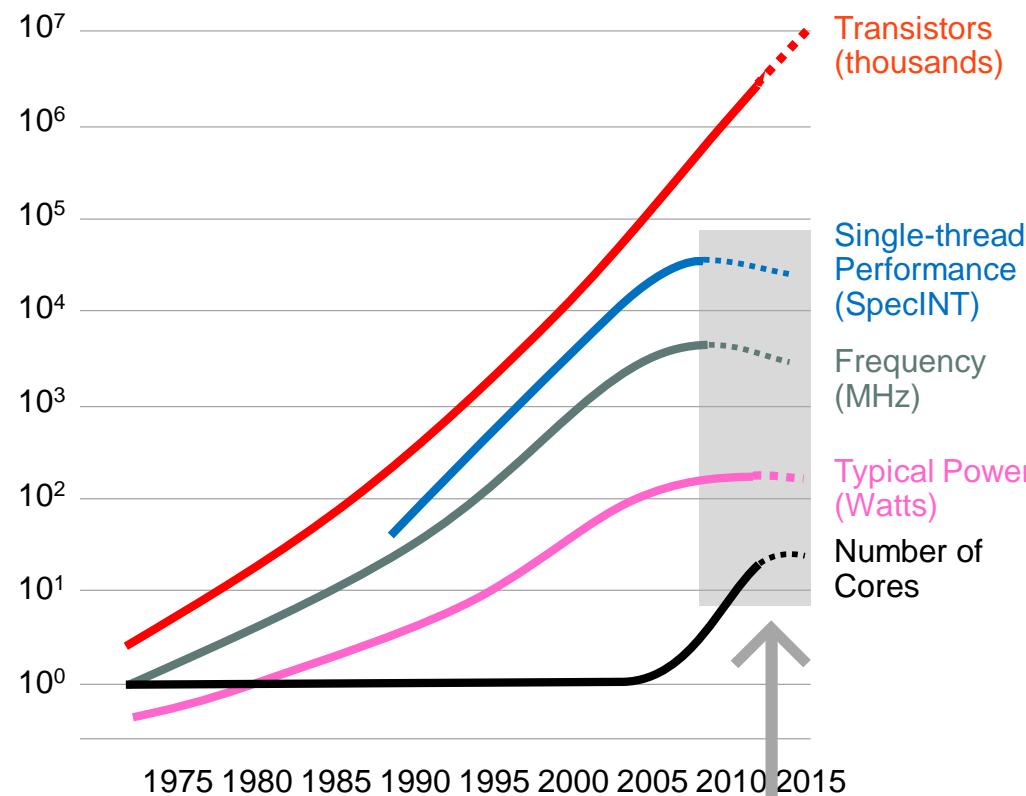
**Di Liang**

Large-Scale Integrated Photonics (LSIP) Group  
Hewlett Packard Labs



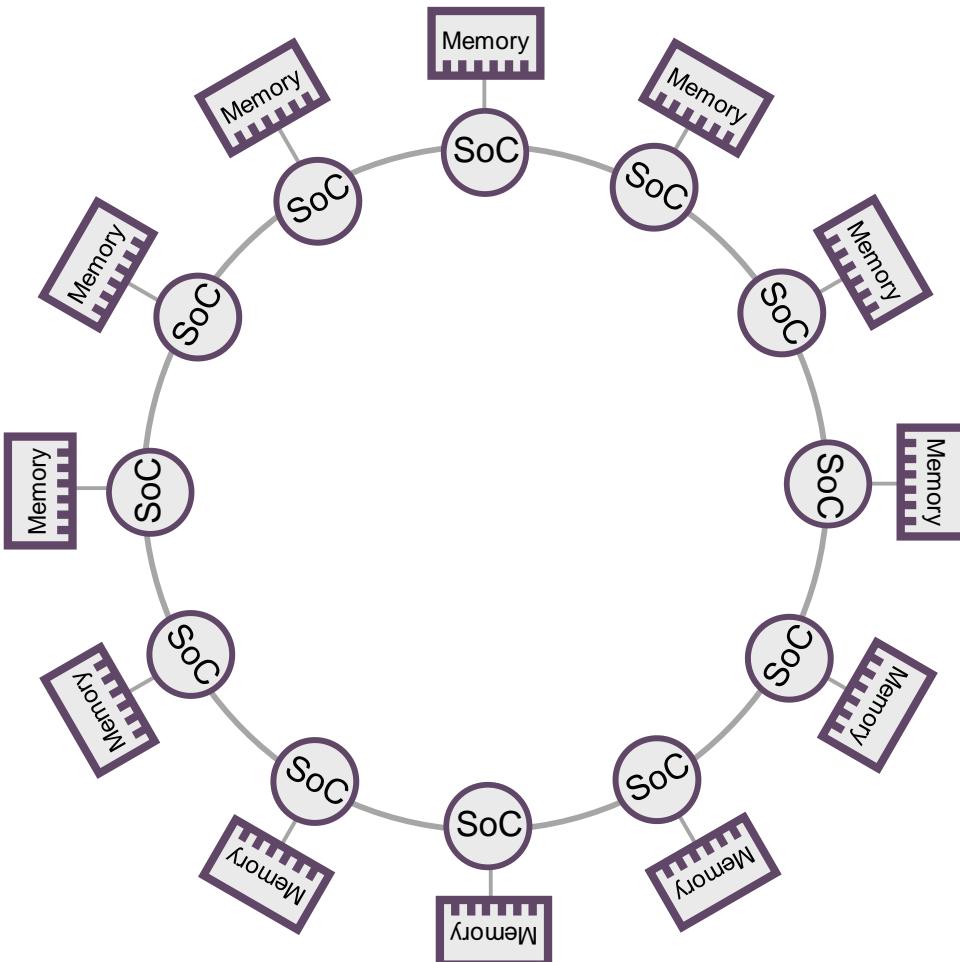
# The end of cheap hardware

Compute is not keeping up

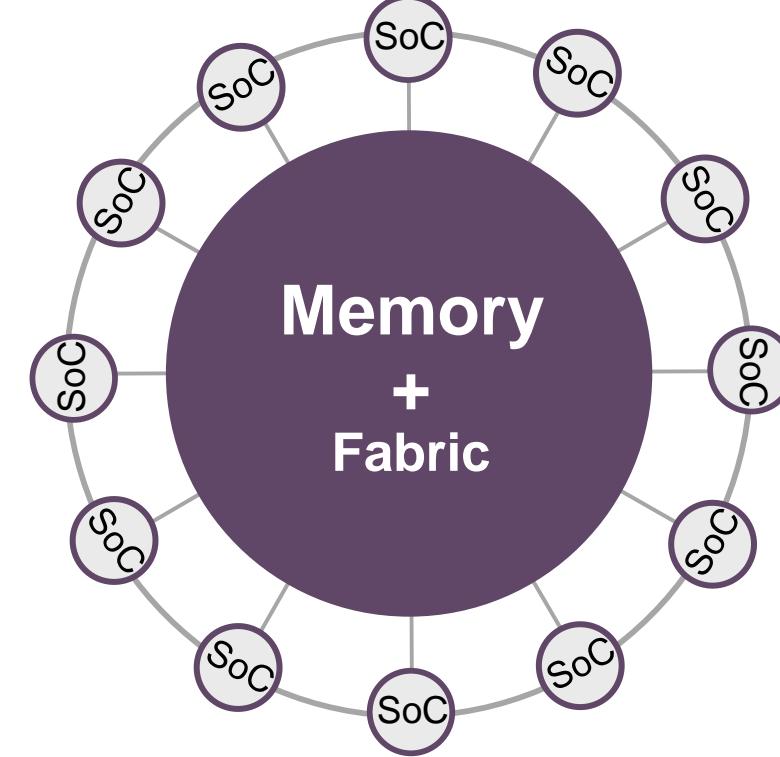


# Memory-driven computing

“The Machine”

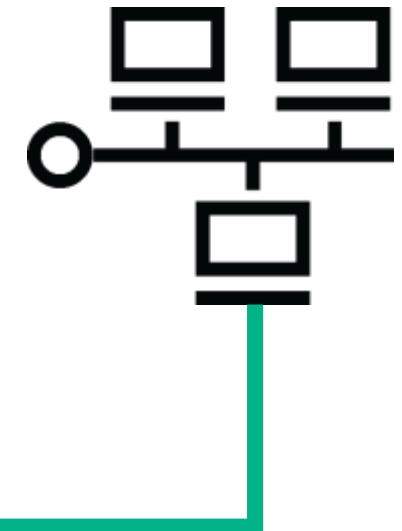
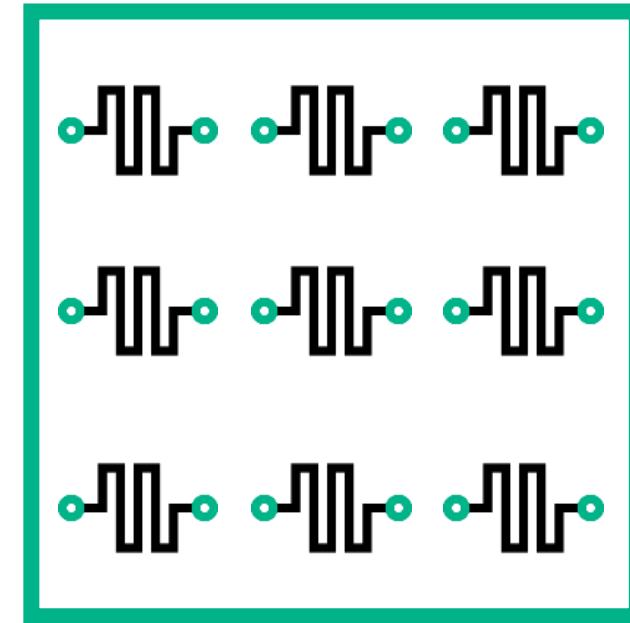
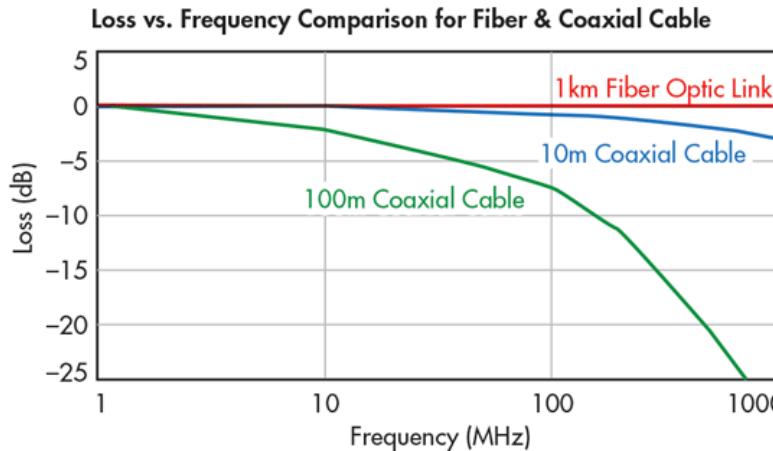
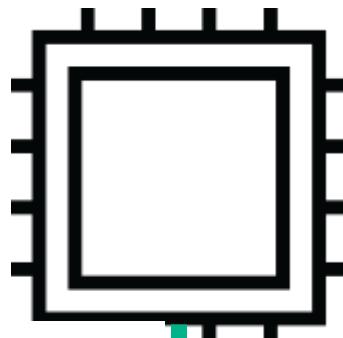


From processor-centric computing...

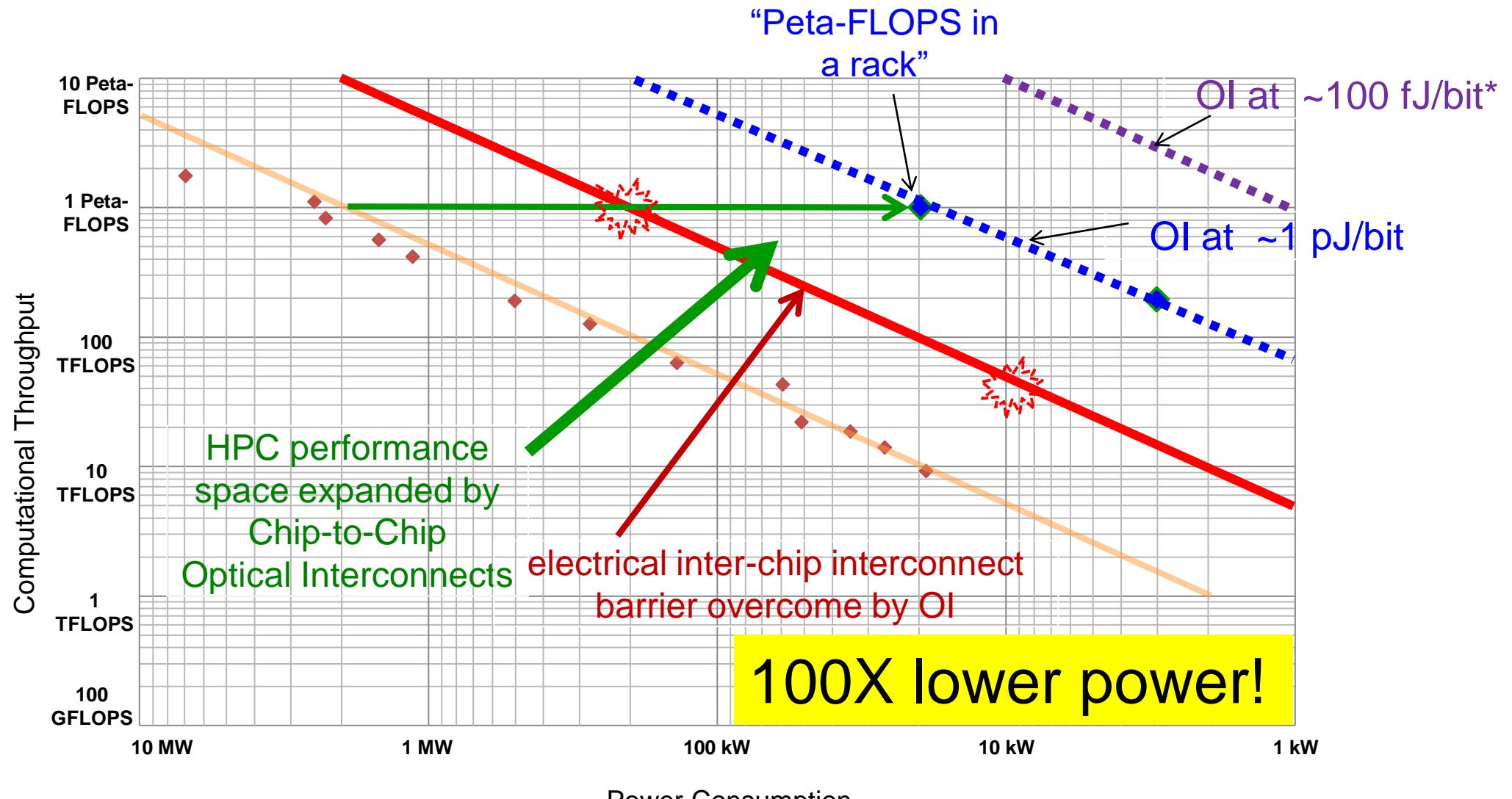


...to Memory-Driven Computing

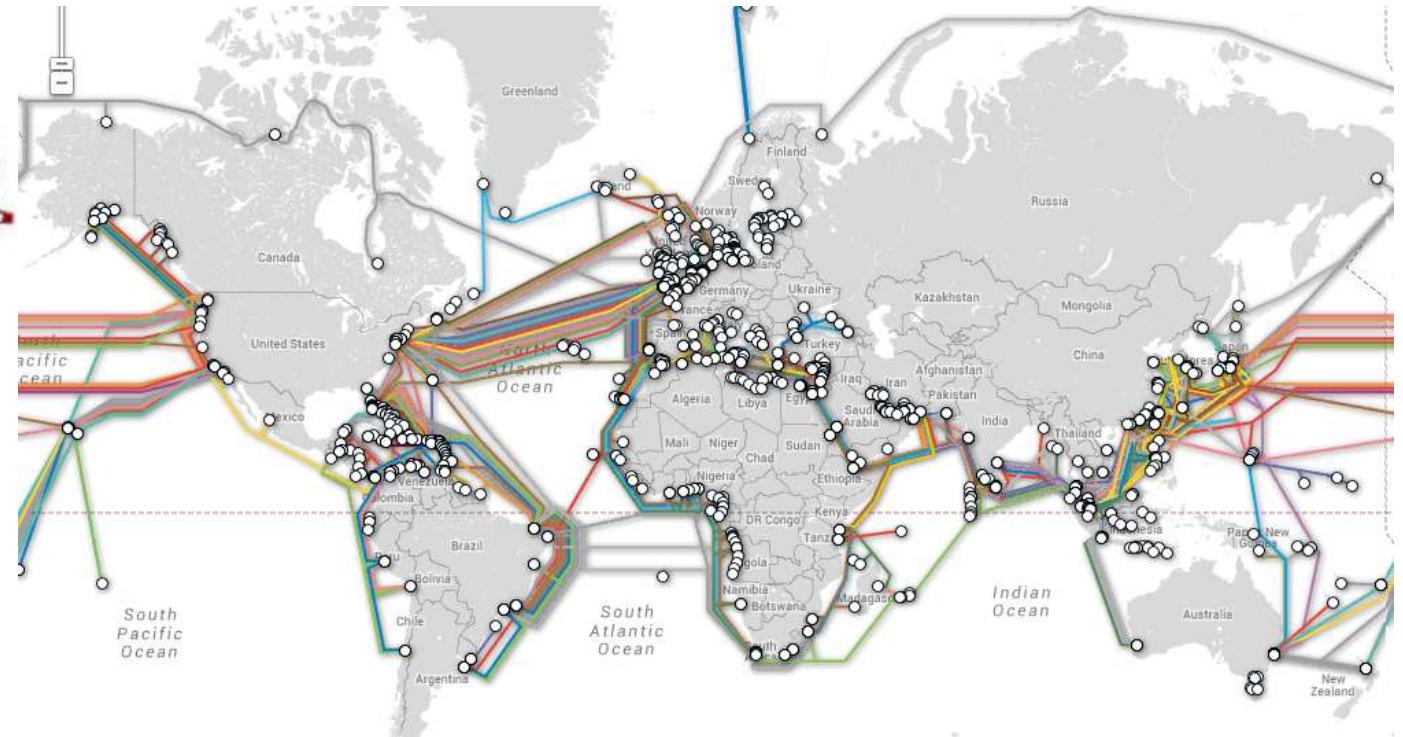
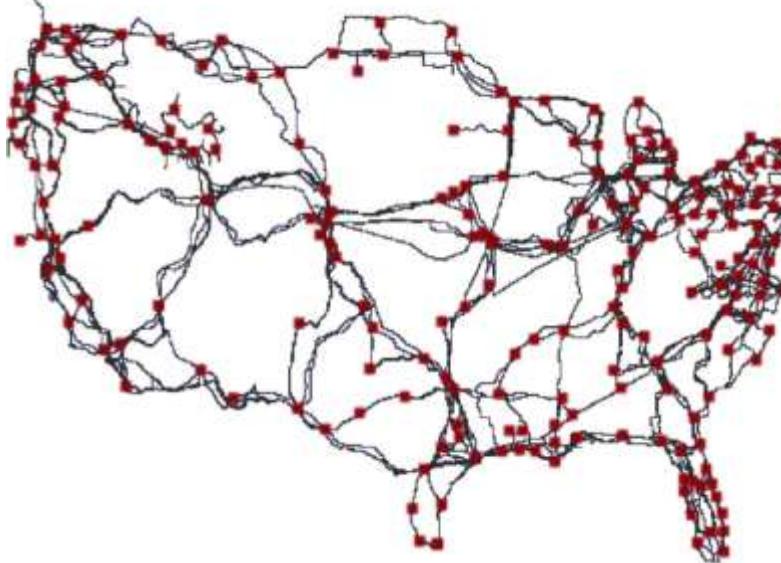
# Moving data in “The Machine” with photons ... from now on



# Electrical vs. optical interconnect



# Moving data around the world with photons ... for decades

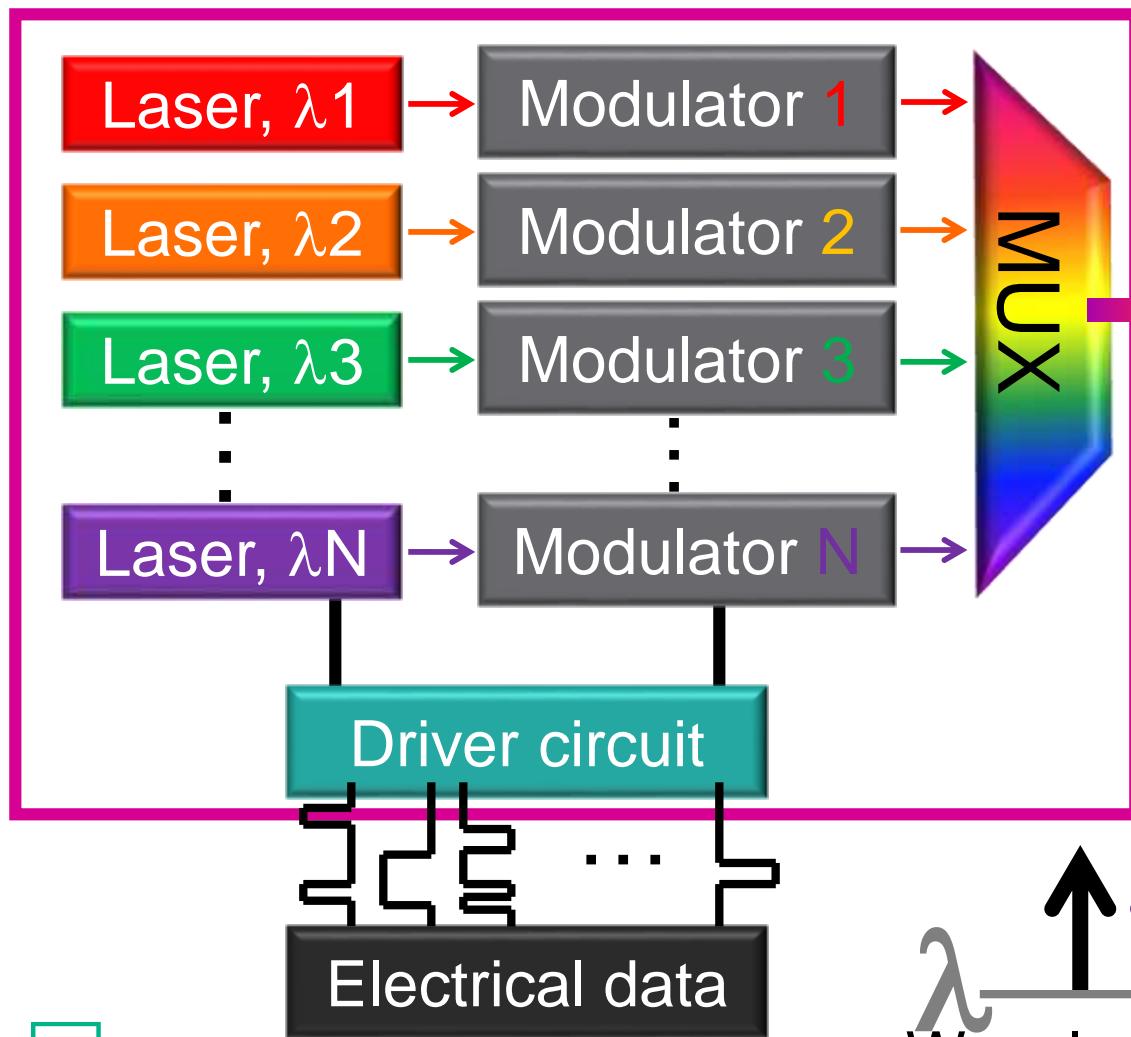


- 1960-70: invention of **optical fiber**, development of GaAs **diode lasers**
- 1970-80: 1<sup>st</sup> generation of commercial fiber-optic network
- 1980- post 1990s: 2<sup>nd</sup>, 3<sup>rd</sup> generations of network
- 2017: KDDI Research and Sumitomo Electric set record (**10.16 Petabit/s**, multi-core fiber, SDM)

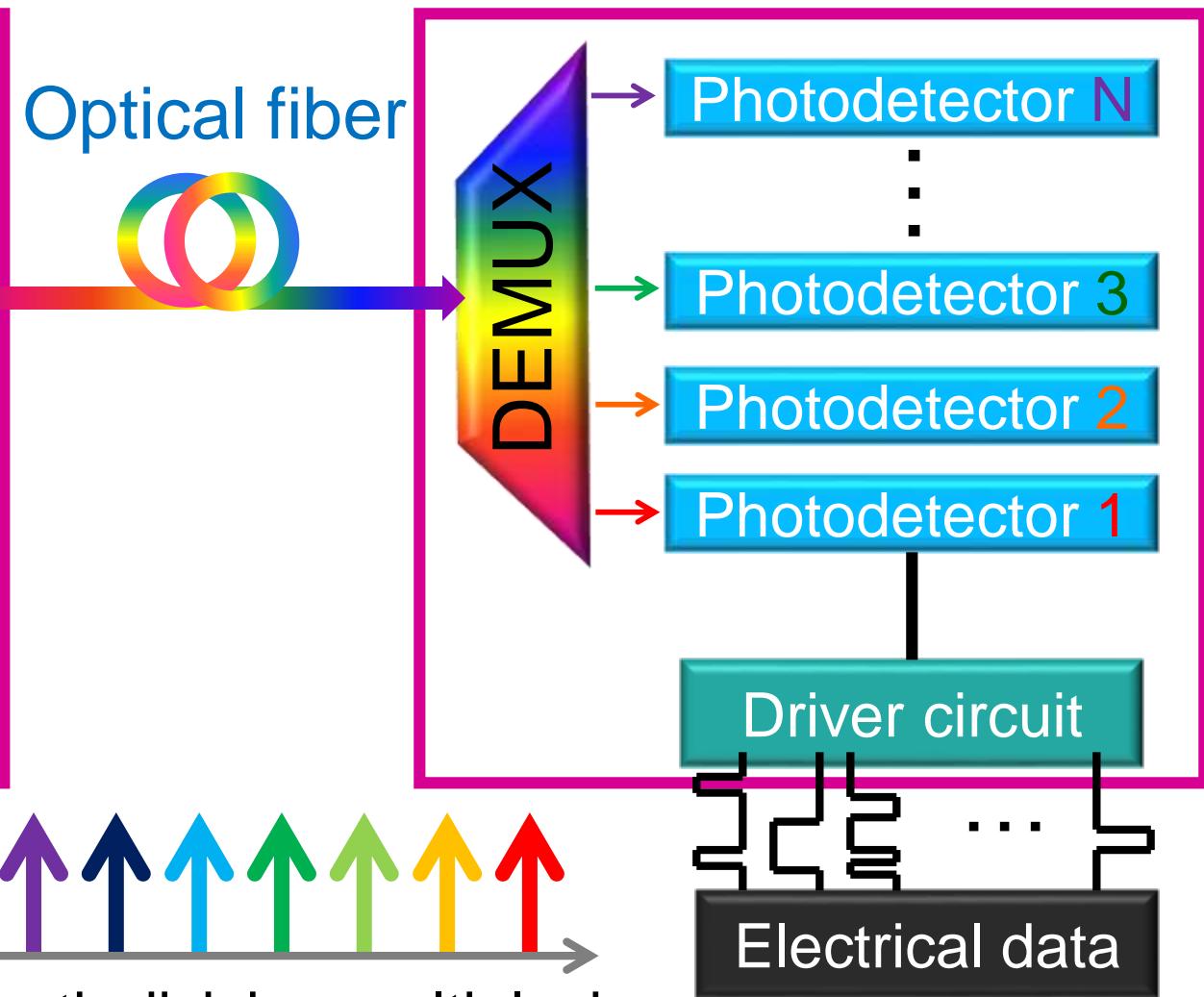


Carry multiple data channels in different **color** of light streams

## Transmitter

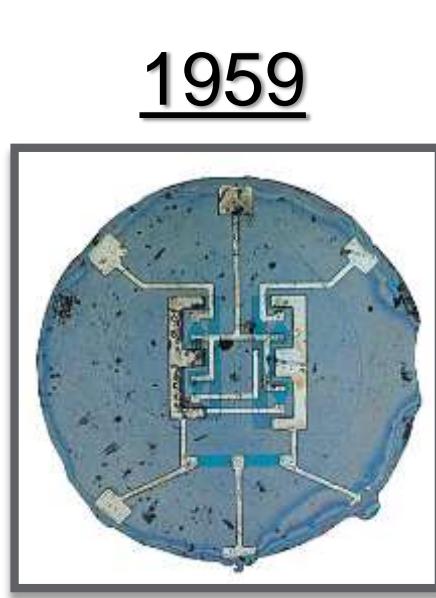


## Receiver



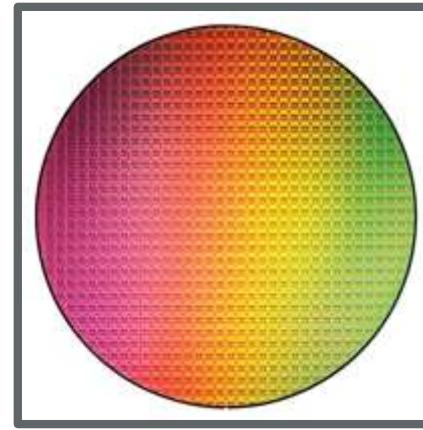
$\lambda$  Wavelength division multiplexing

# Microelectronic integration vs. photonic integration

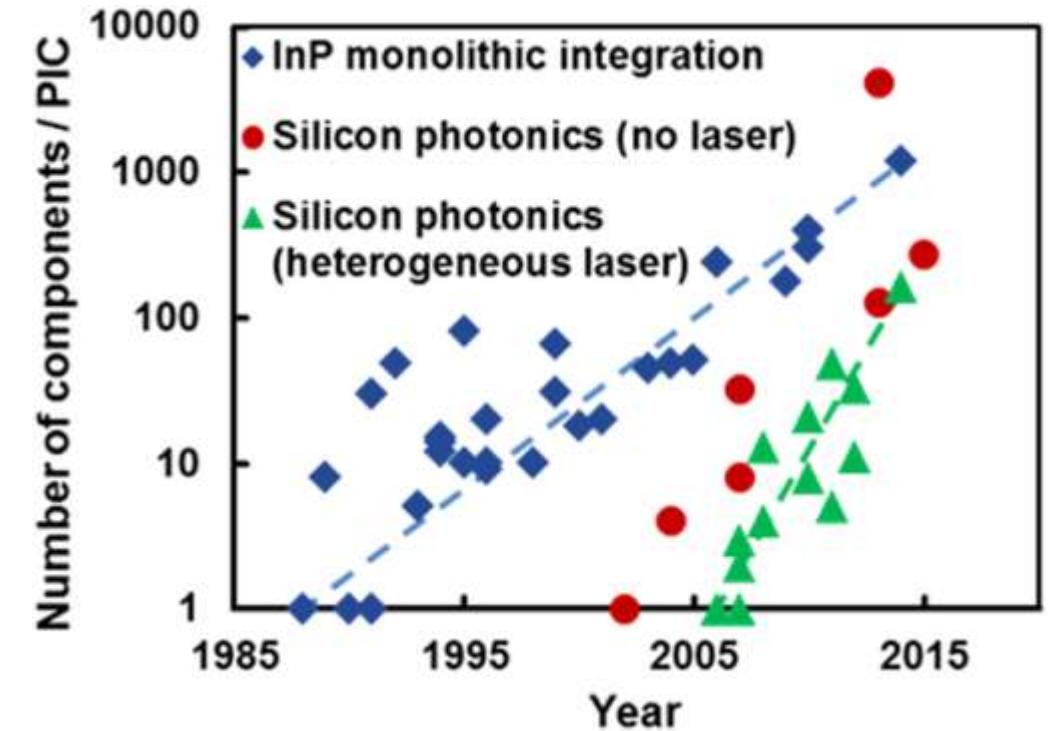


**Silicon**

~50 years



Today



Heck, JSTQE 19, 6100117(2013)

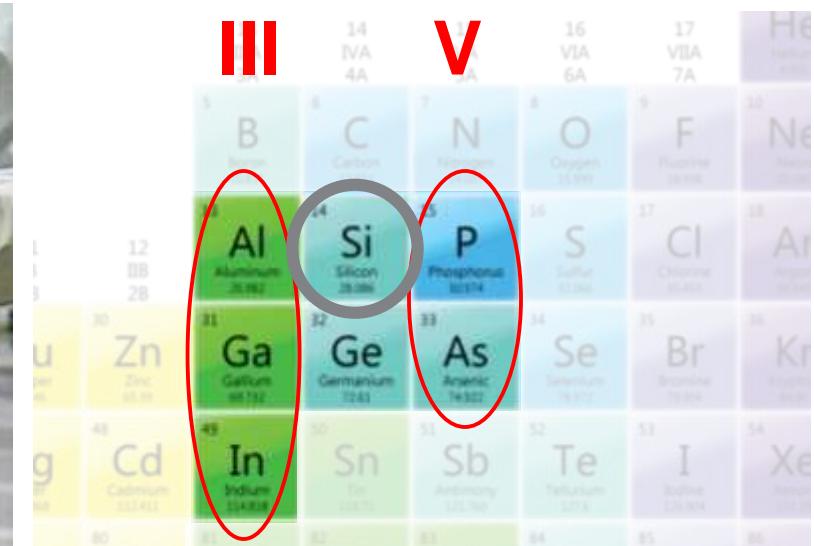
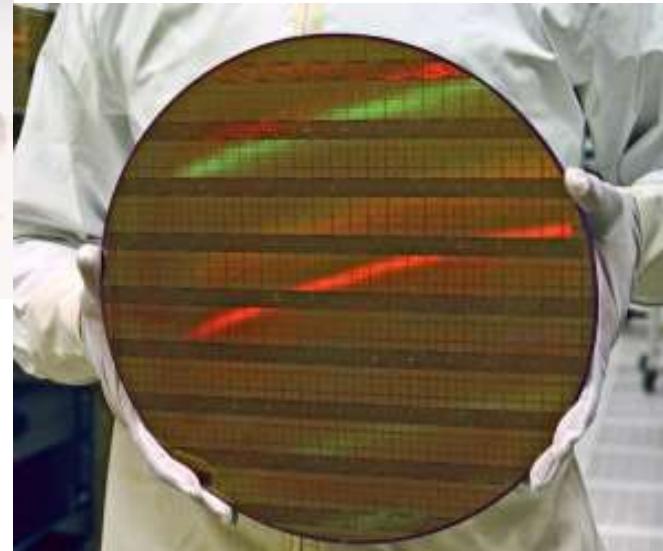
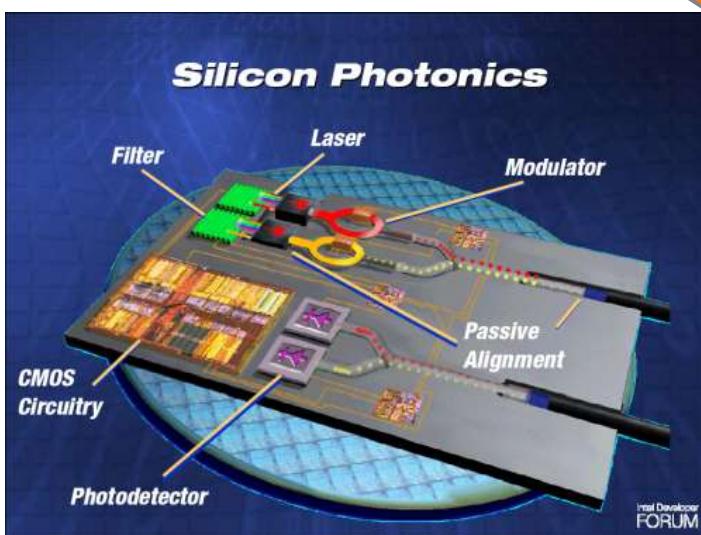
- Microelectronic integration: device size, wafer scale, manufacture technique
- Photonic integration: functionality, material and fabrication compatibility

# How to build low-cost photonic integrated circuits (PICs)?

>\$1000/module

III-V  
2, 3, 4 inch

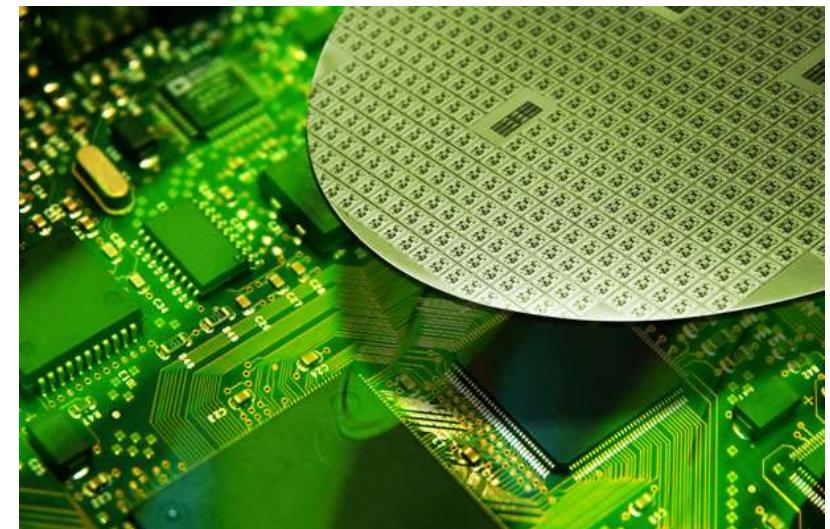
Courtesy: Intel



Silicon  
12, 18 inch

<\$1/module

\$/chip



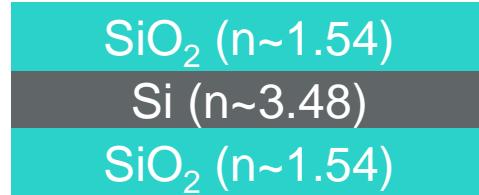
<http://sciencenotes.org/printable-periodic-table/>

[http://www.evgroup.com/images/content/78745/multi-junction\\_concentrator\\_solar\\_cell.jpg](http://www.evgroup.com/images/content/78745/multi-junction_concentrator_solar_cell.jpg)

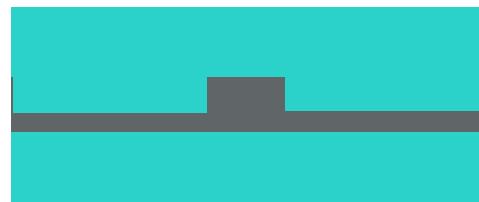
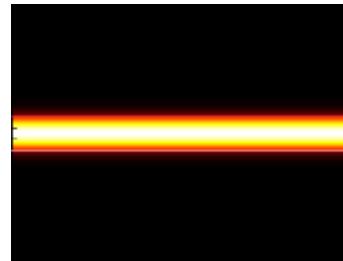
<http://www.bit-tech.net/news/hardware/2012/07/10/intel-invests-asml/1>

# Basic planar waveguide structure on silicon

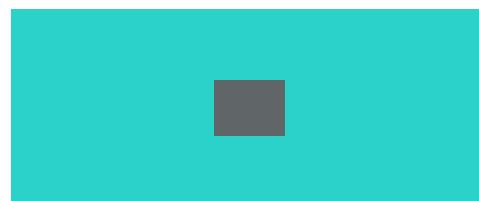
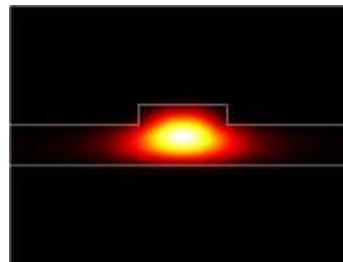
Waveguide cross-section



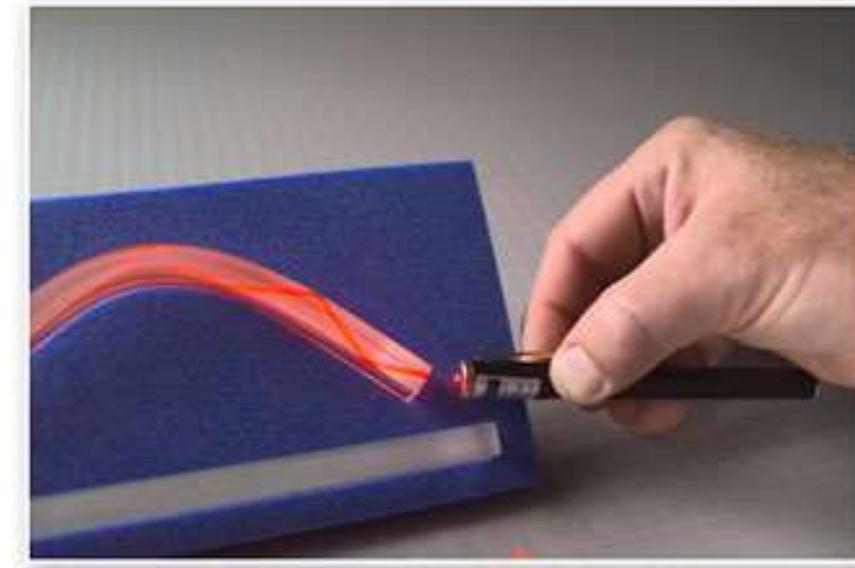
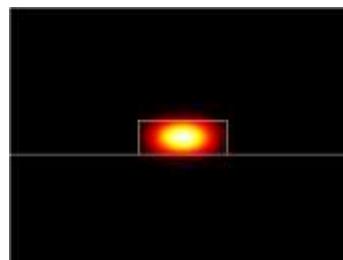
Slab waveguide



Rib/ridge waveguide

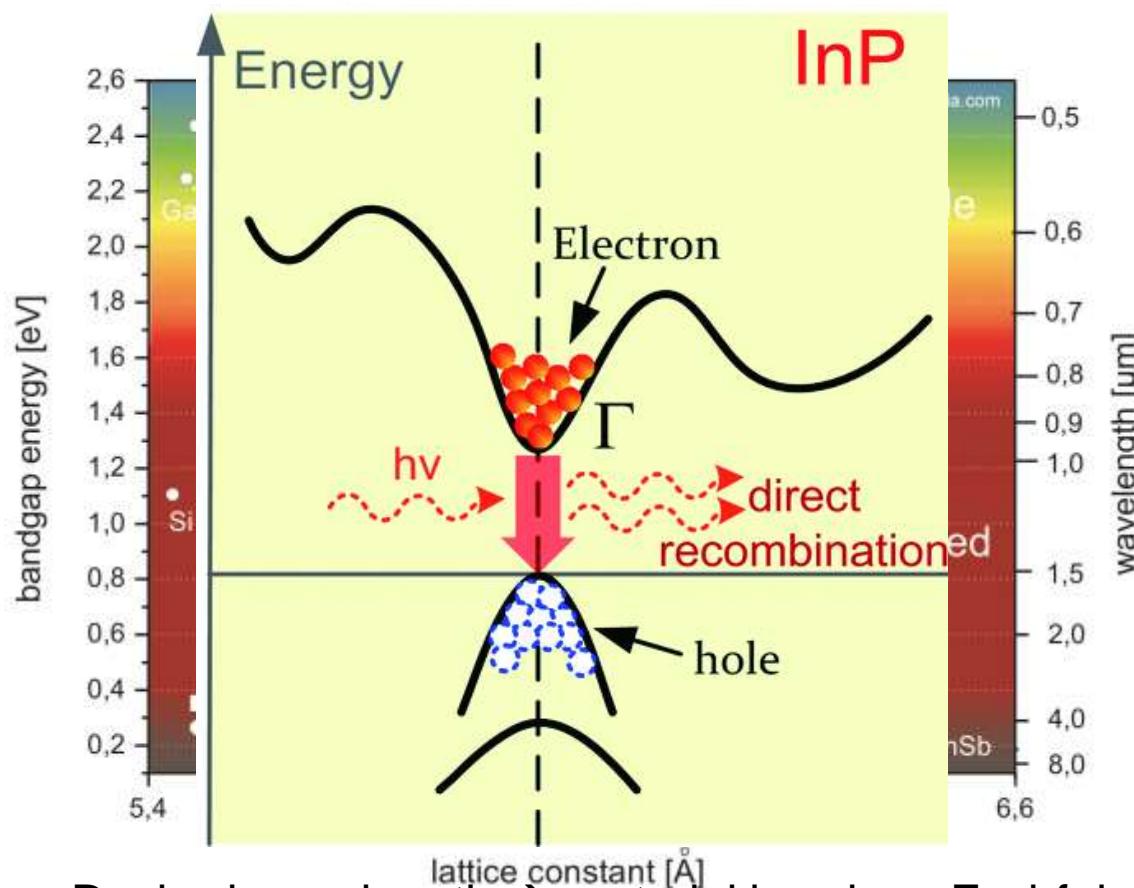


Stripe waveguide

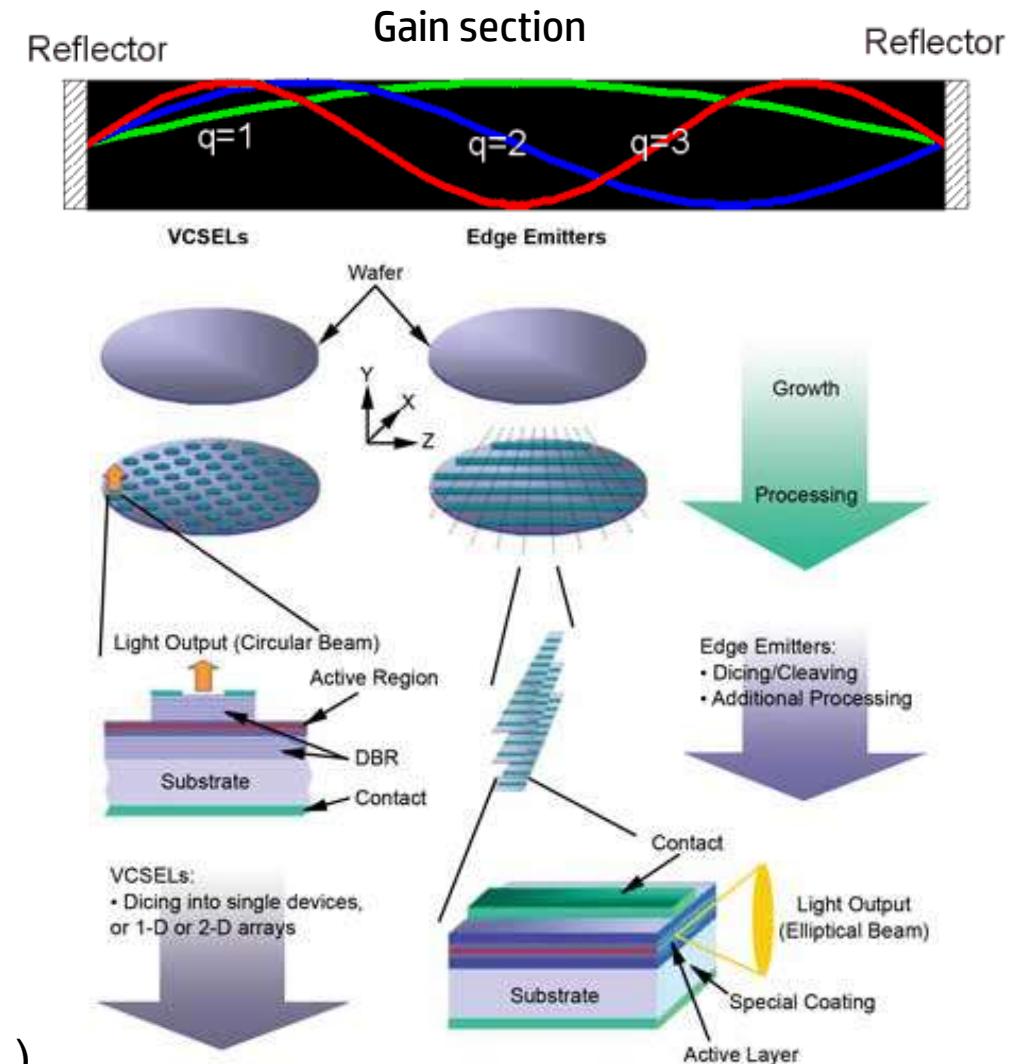


- Larger index contrast  
 $\Delta n = n_{\text{core}} - n_{\text{cladding}}$ 
  - smaller single-mode waveguide
  - better mode confinement → smaller bending loss
  - higher scattering loss if sidewall is rough

# Light source: diode lasers

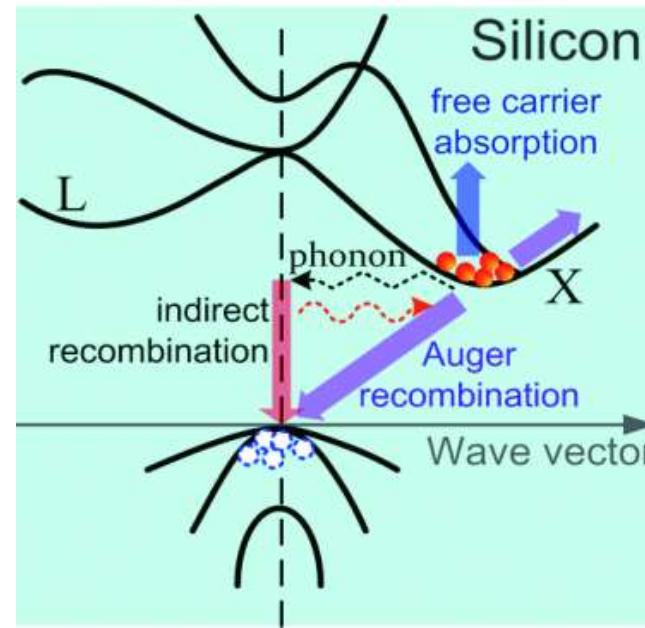
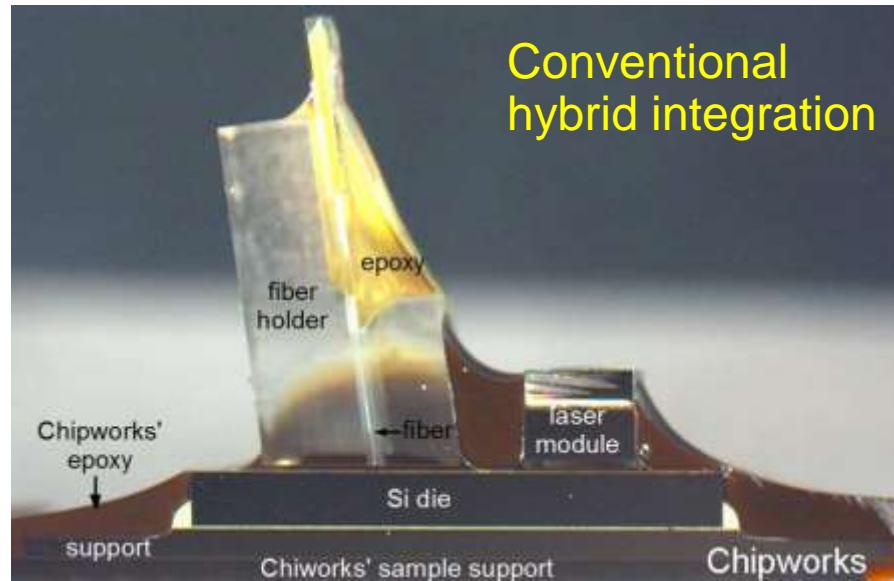


- Desired wavelength  $\rightarrow$  material bandgap  $E_g = hf = hc/\lambda$
- Direct bandgap material
- Difficult to manufacture (purity, fabrication, reliability ...)

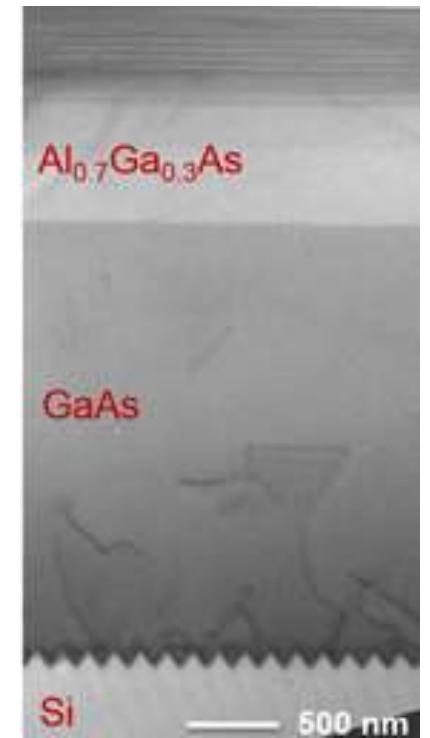


Optical gain inside a resonator

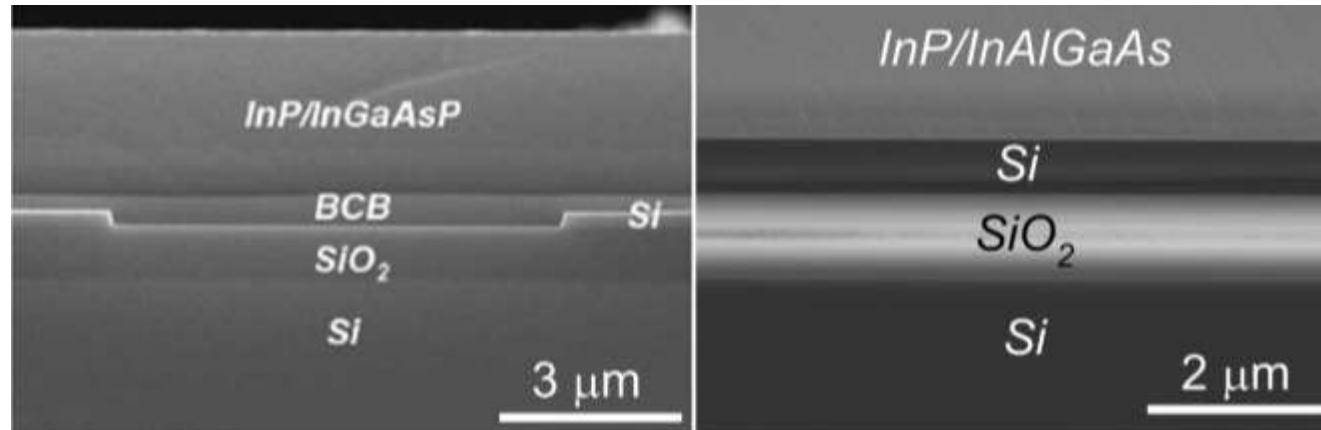
# Integrating lasers/lasing materials on silicon



Monolithic integration

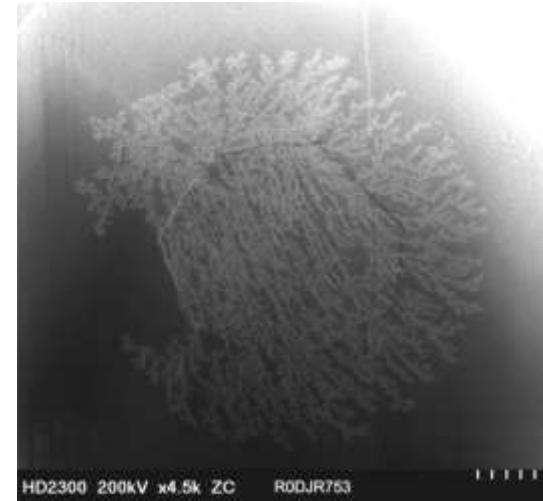
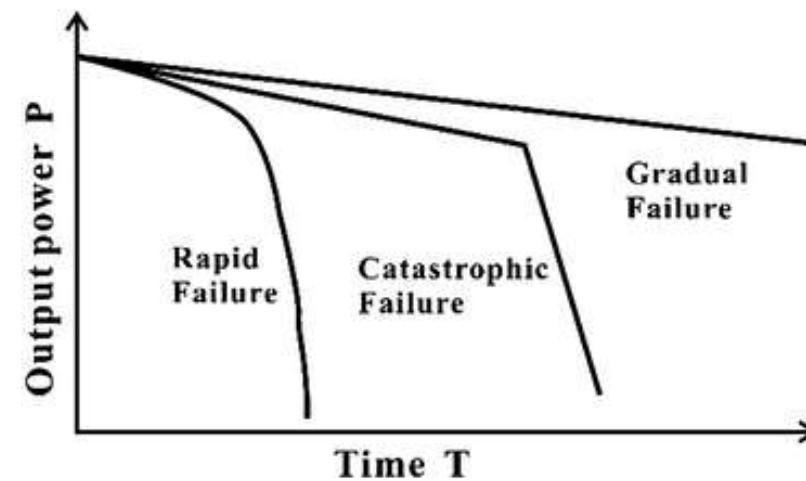
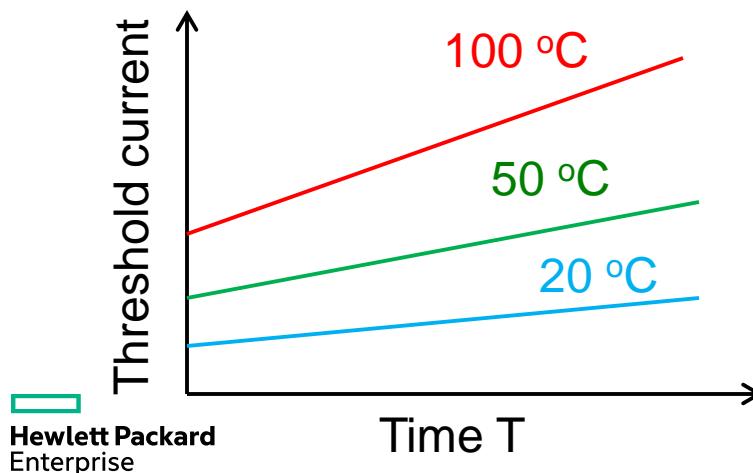


Heterogeneous integration

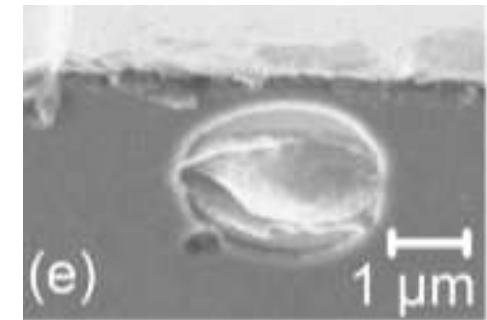


# Reliability issues in diode lasers

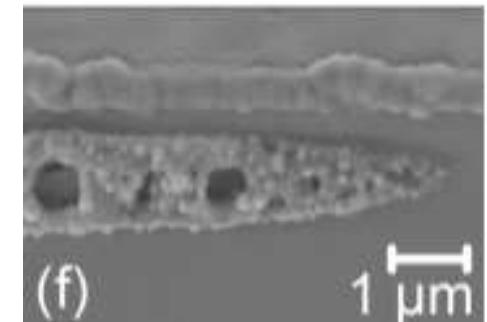
- Typical diode laser degradation modes:
  - Active region – crystalline defects, operation
  - Mirror facets – impurity, crystalline defects
  - Carrier lateral confinement – crystalline defects
  - Ohmic contacts – fabrication, packaging
  - Electrical overstress and electrostatic discharge – packaging, handling
  - Mechanical stability – packaging, operation condition, environment



Courtesy of R. Herrick (Intel)



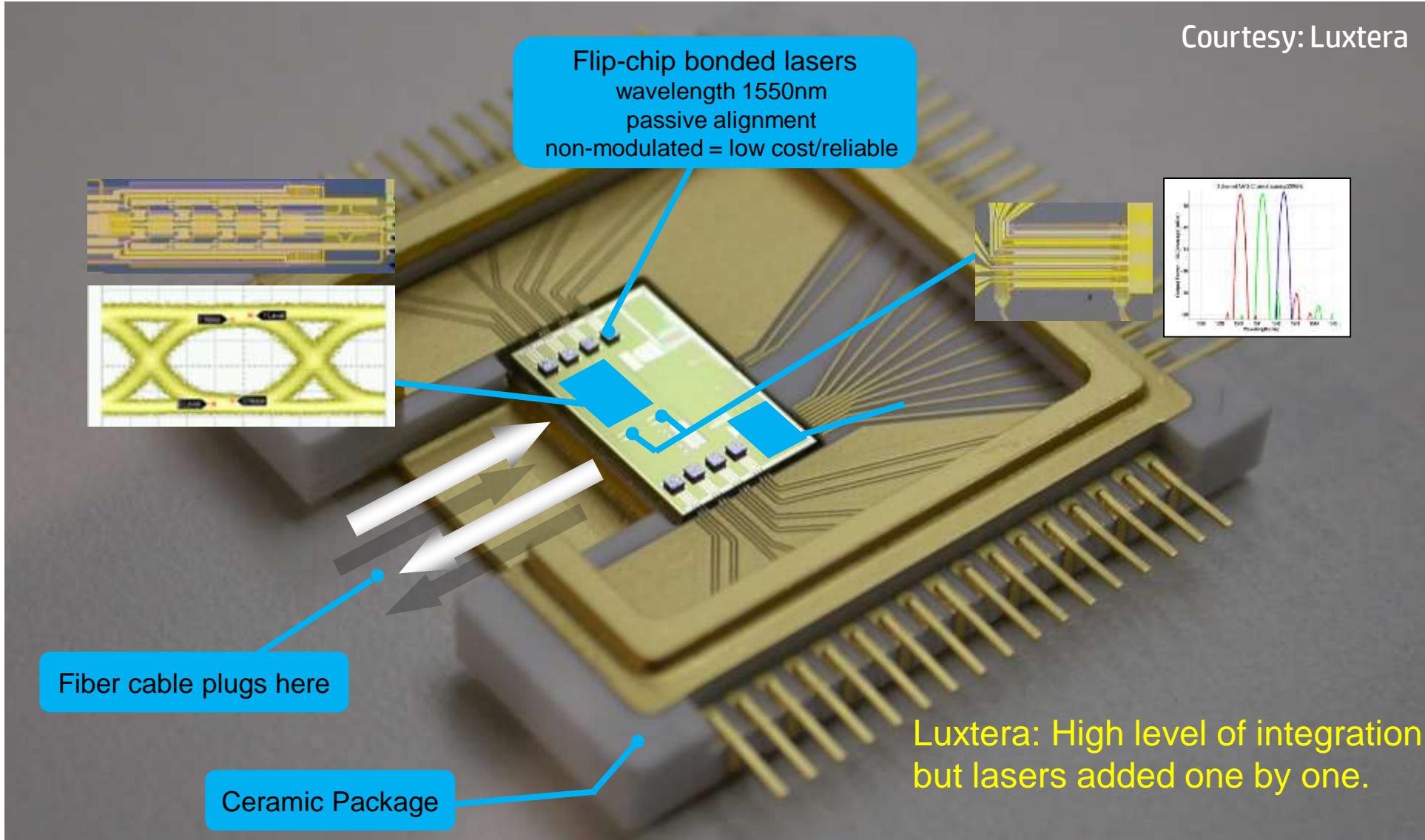
(e)



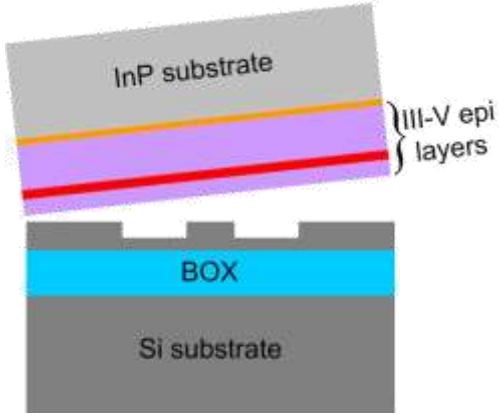
(f)

Hempel, CLEO (2011)

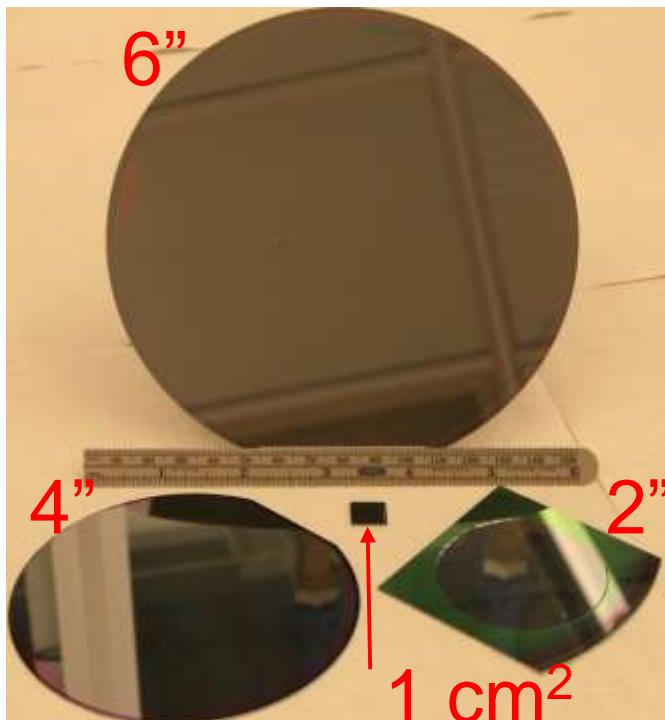
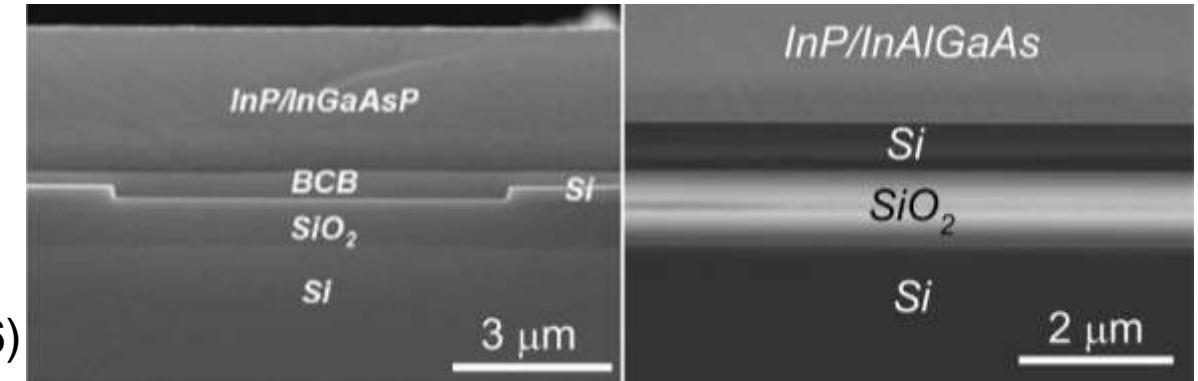
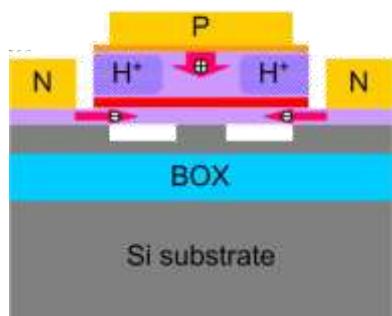
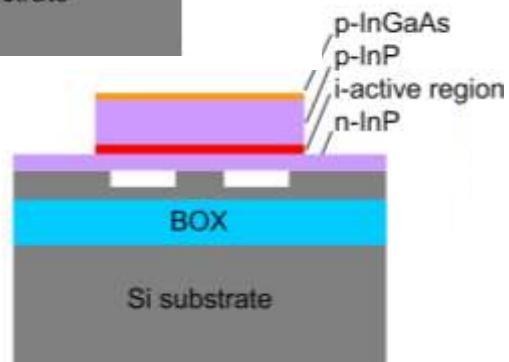
# Conventional hybrid integration



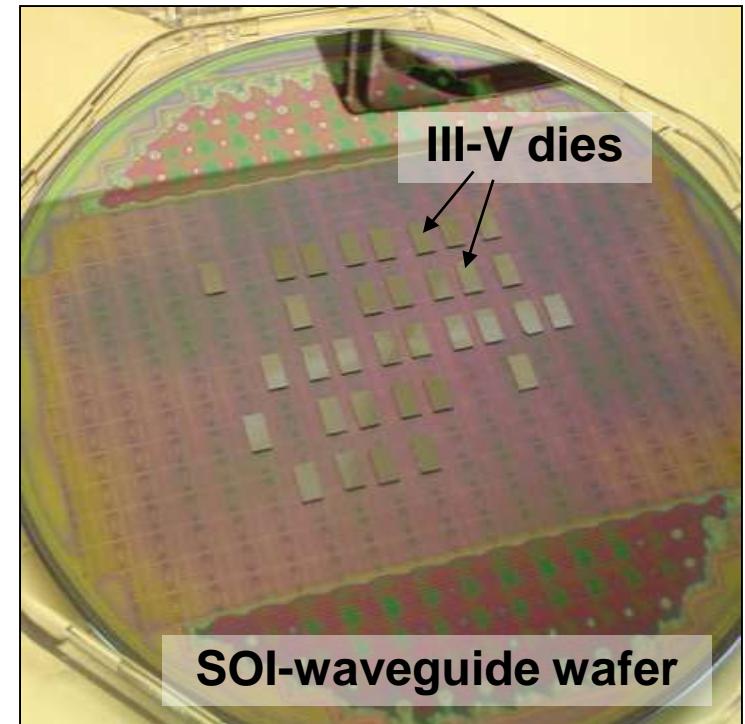
# Heterogeneous integration



Park, OE, **12**, 9460 (2005)  
Fang, OE, **14**, 9203 (2006)  
Roelkens, OE, **14** 8154 (2006)

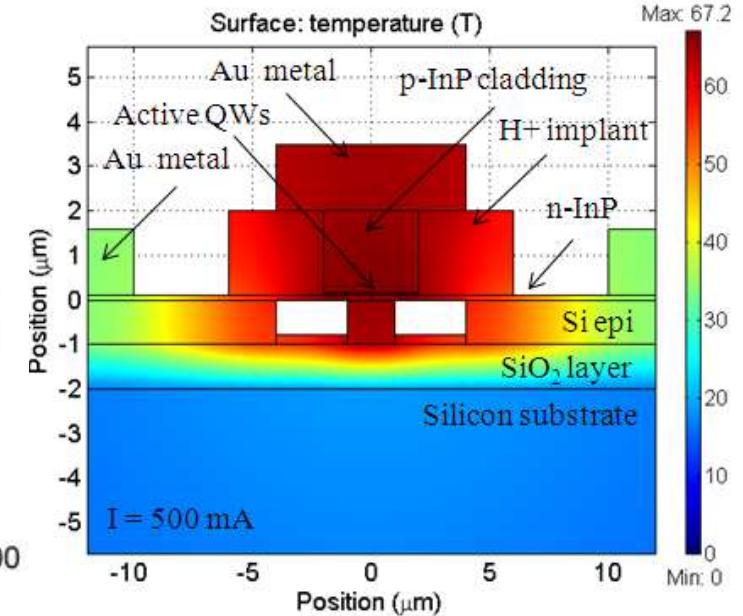
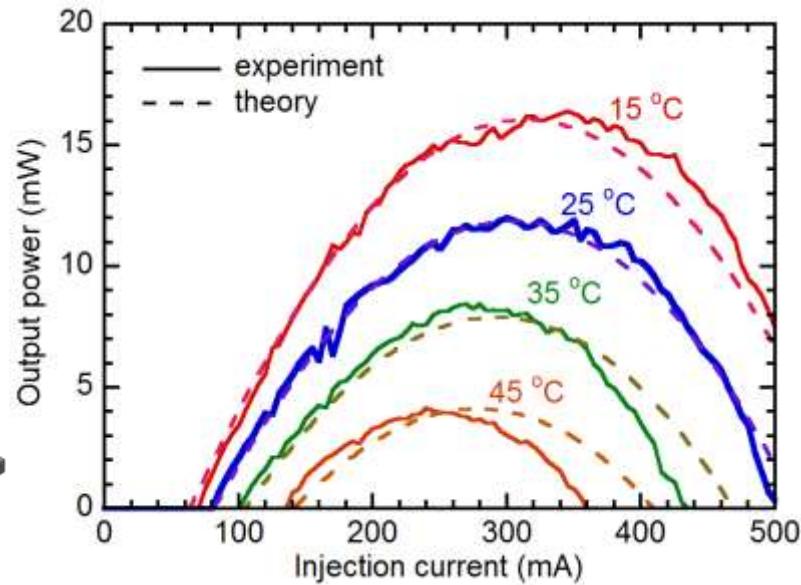
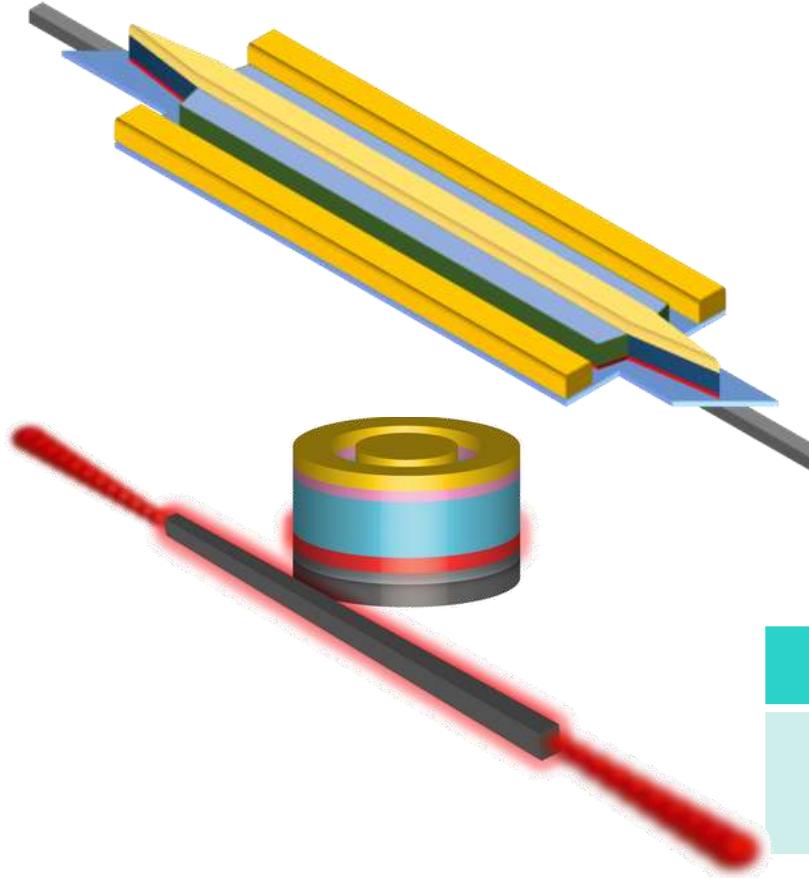


Liang, ESSL **12**, H101 (2009)



Fedeli, AOT **2008**, 412518 (2008)

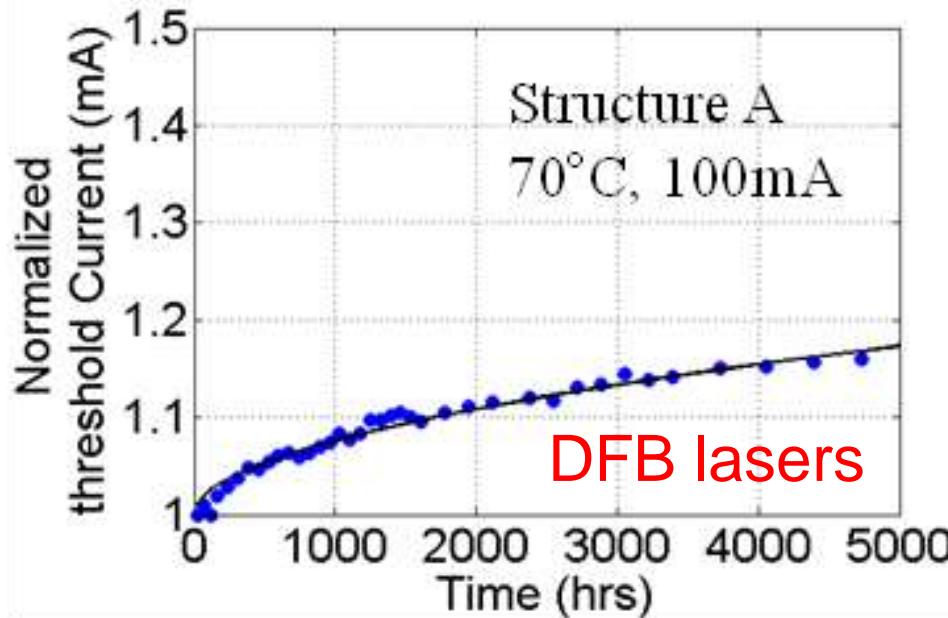
# A major performance bottleneck: thermal management



Material	InP	Si	SiO <sub>2</sub>	Au
Thermal conductivity (W/m-K)	70	130	1.3	317

# Reliability studies on heterogeneous lasers

- DFB lasers: estimated 50% degradation in threshold current at 70 °C for ~40000 hrs
- DBR lasers: degradation likely from impurity diffusion towards the active region.

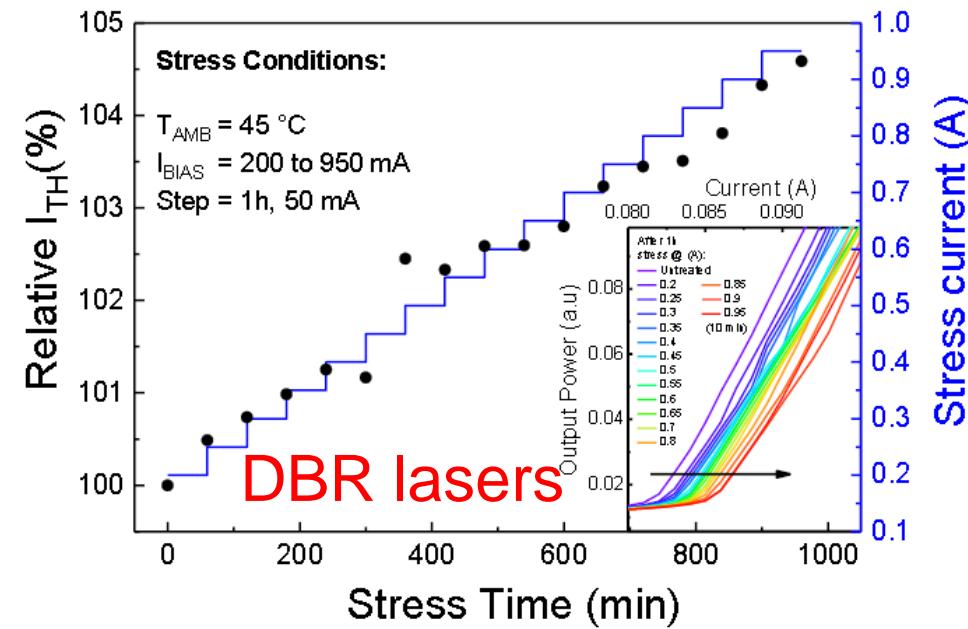


Hewlett Packard  
Enterprise

Srinivasan, JSTQE 19, 1501305 (2013)

$$I_{th}/I_{th}(0) = 1 + at^m$$

$$MTTF = \left( \frac{0.5}{a} \right)^{\frac{1}{m}}$$

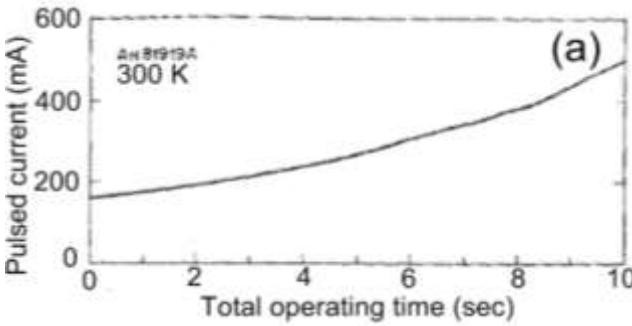


Buffolo, Proc. SPIE 10537, 105370X (2018)

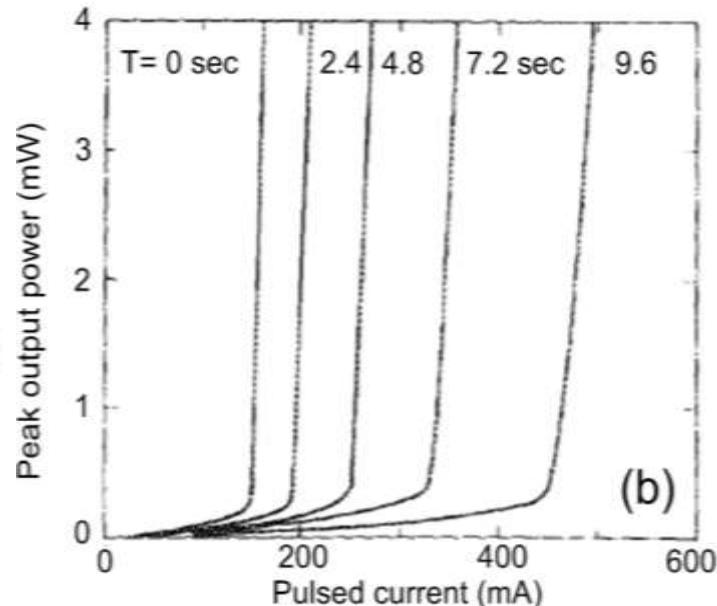
# Monolithic integration

## Main challenges:

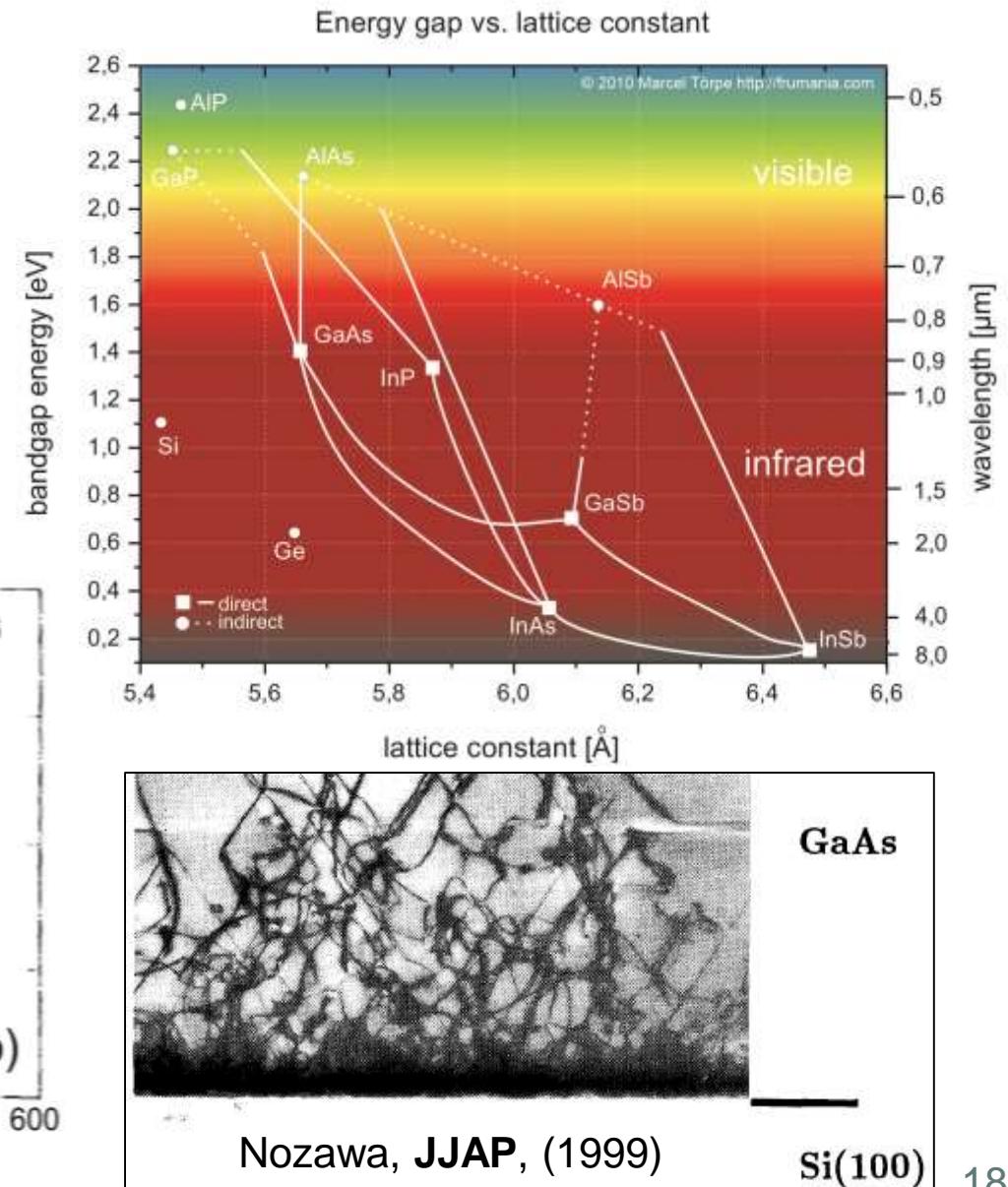
- Lattice mismatch (~4-8% for GaAs, InP vs. Si)
- Anti-phase domains, stacking faults
- Mismatch of thermal expansion coefficient



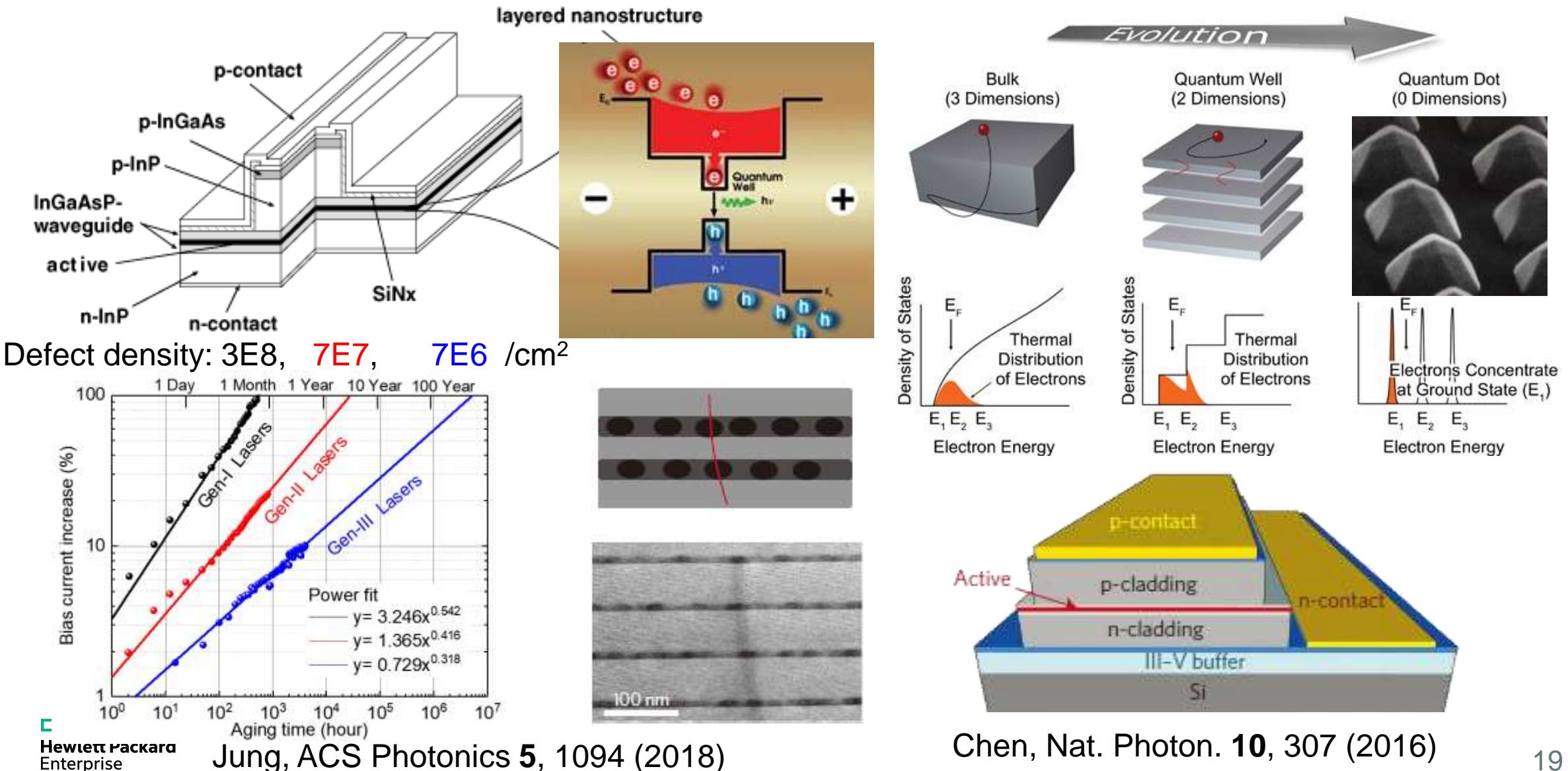
van der Ziel, APL 51, 89 (1987)



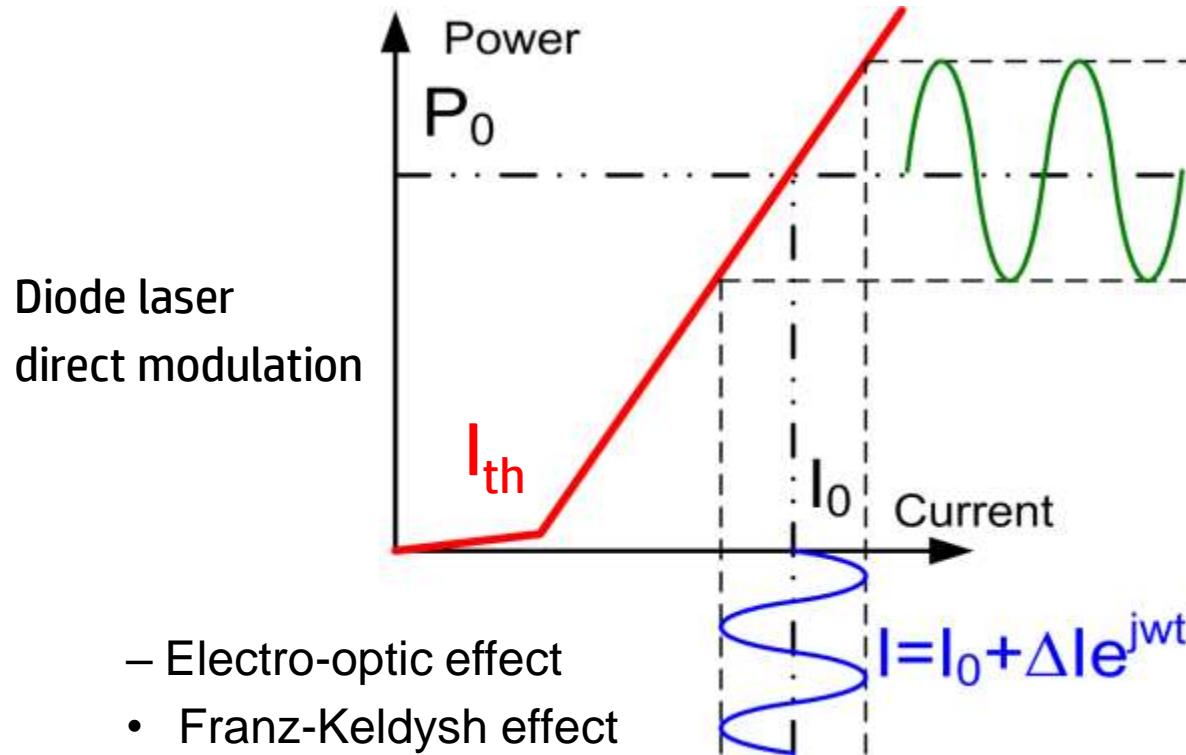
Hewlett Packard  
Enterprise



# Growing defect-tolerant active region: quantum dot



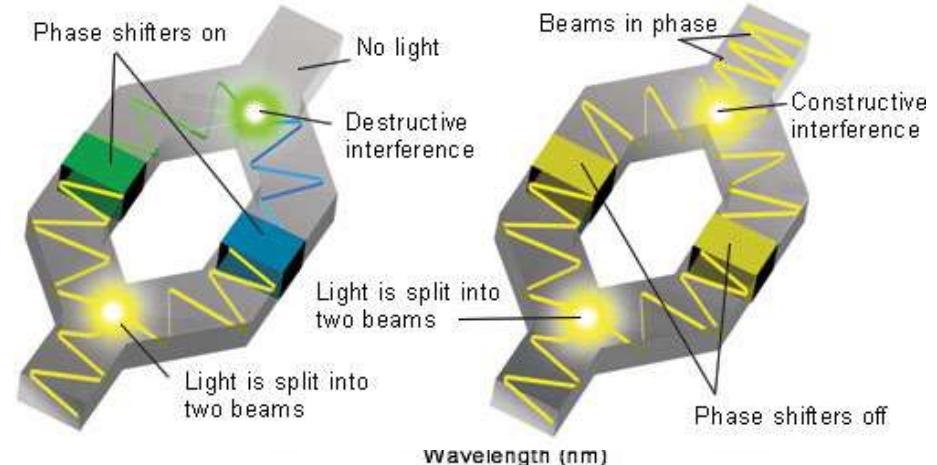
# Optical signal modulation



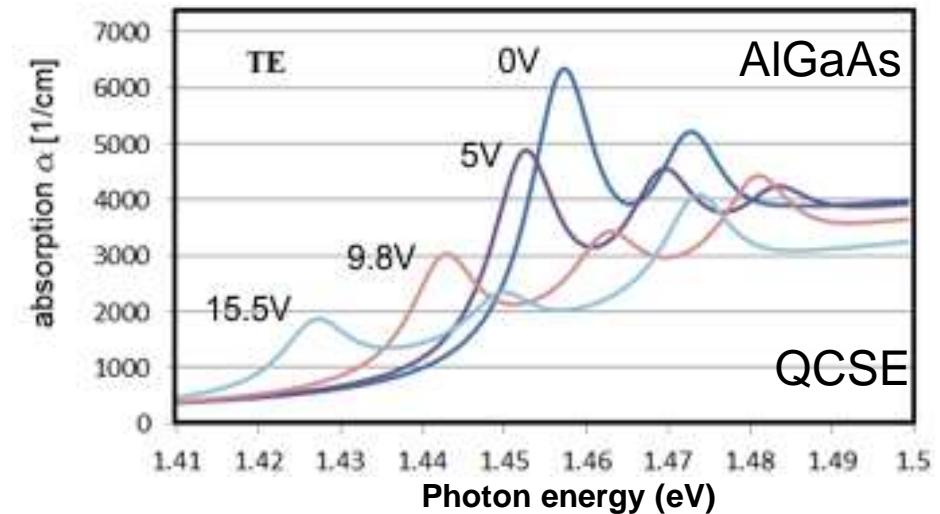
- Electro-optic effect
  - Franz-Keldysh effect
  - Pockels effect
  - Kerr effect
  - Band-filling effect
  - Quantum-confined Stark effect (QCSE)
  - **Plasma dispersion effect**

## External modulation

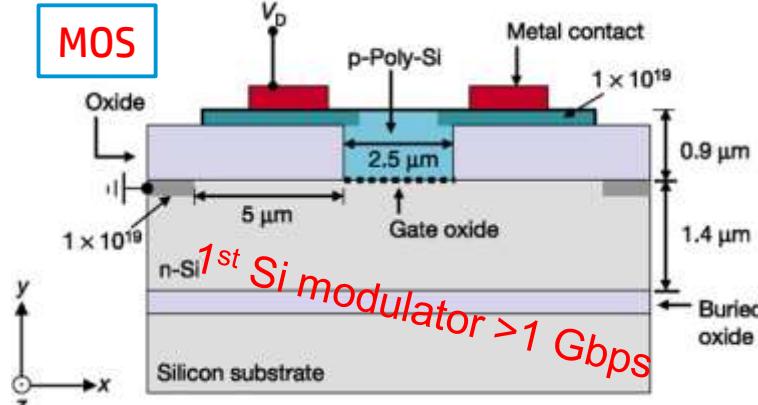
### a. Phase (index) modulation



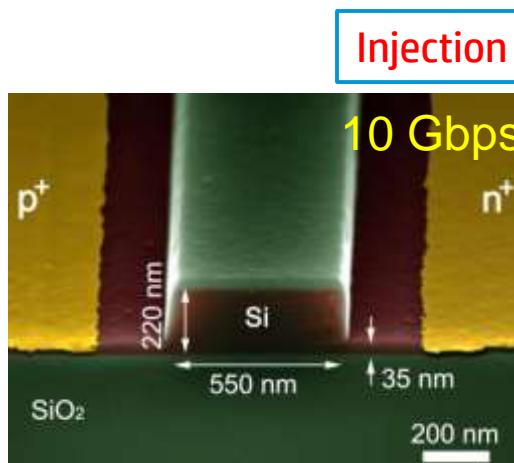
### b. Amplitude (loss) modulation



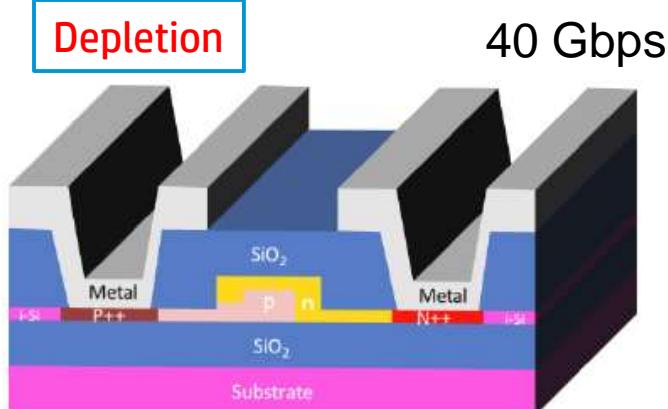
# Silicon modulators



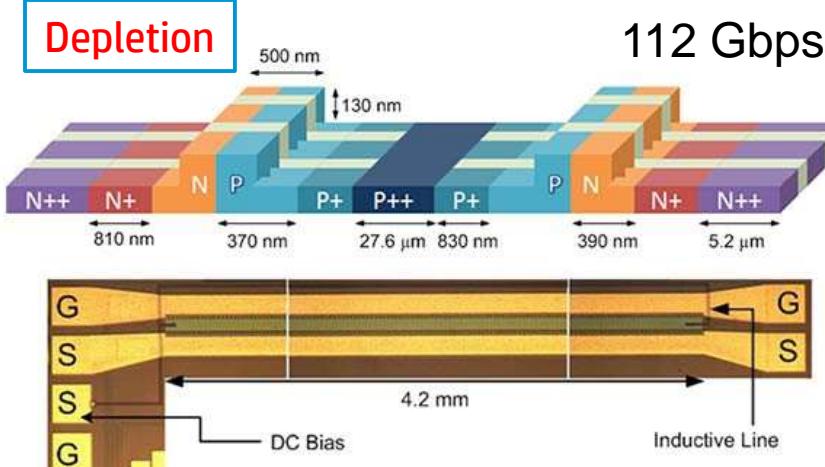
Liu, Nature 427, 615 (2004)



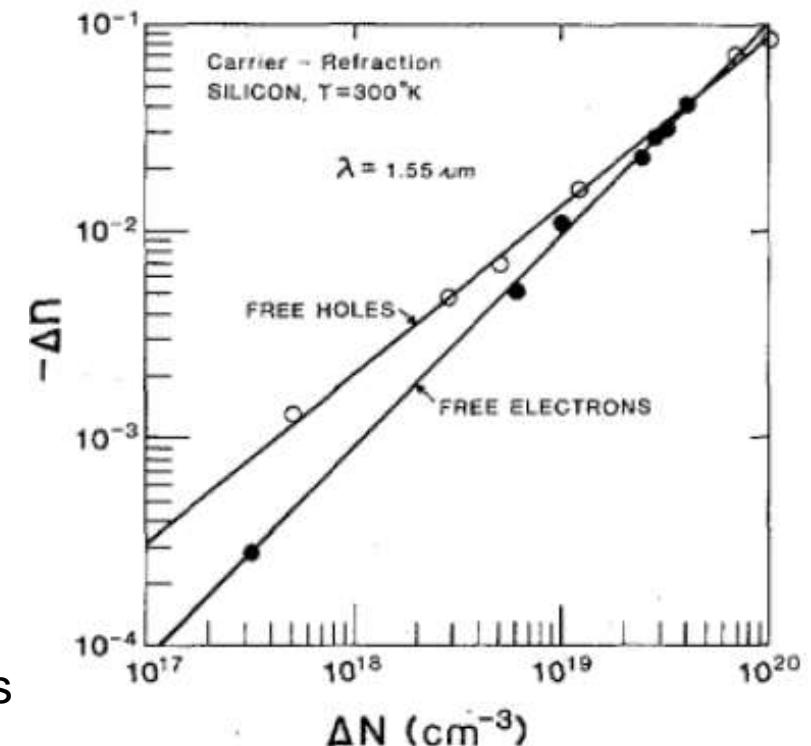
Green, OE 15, 17106 (2007)



Gardes, OE 19, 11804 (2011)



Samani, PJ 7, 7901413 (2015)

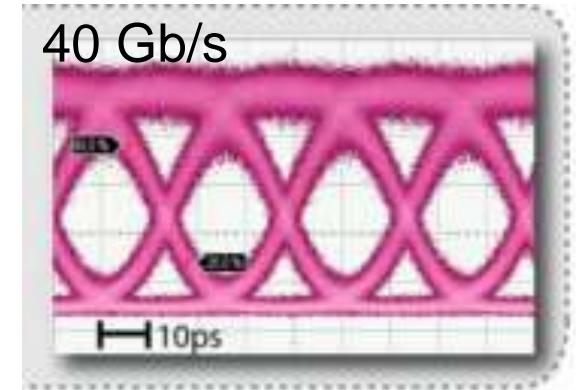
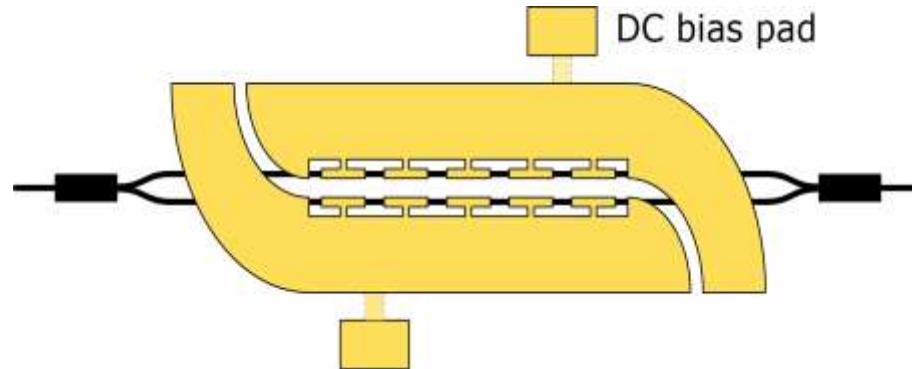
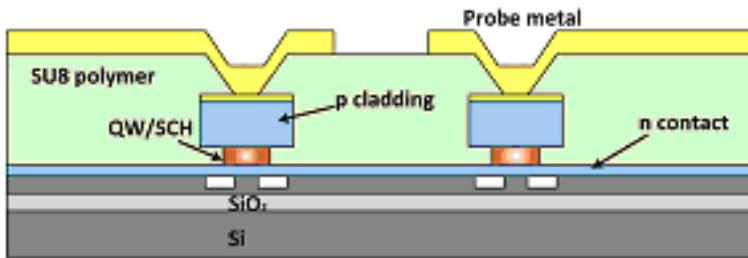


Sorel, JQE QE-23, 123 (1987)

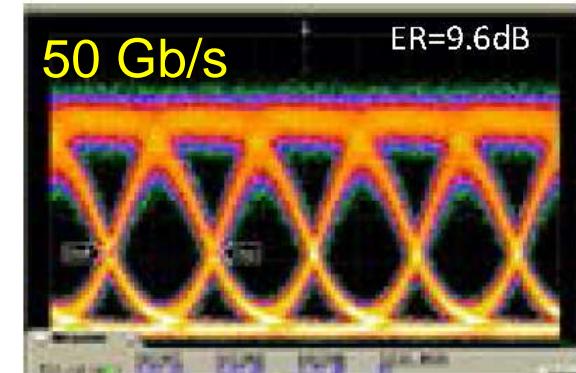
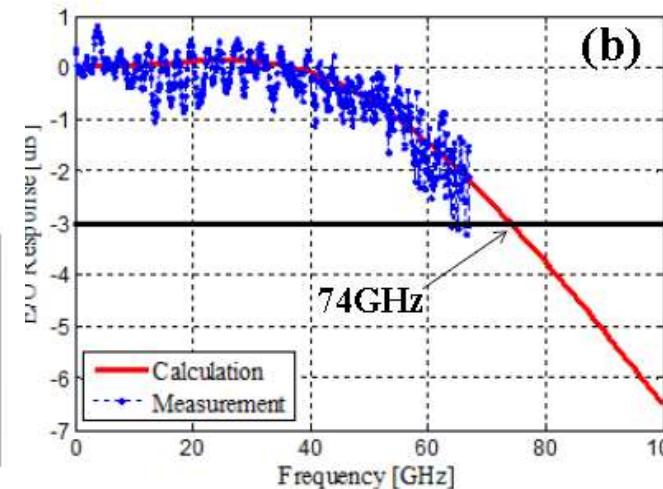
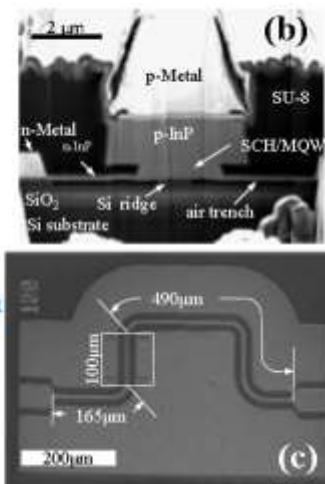
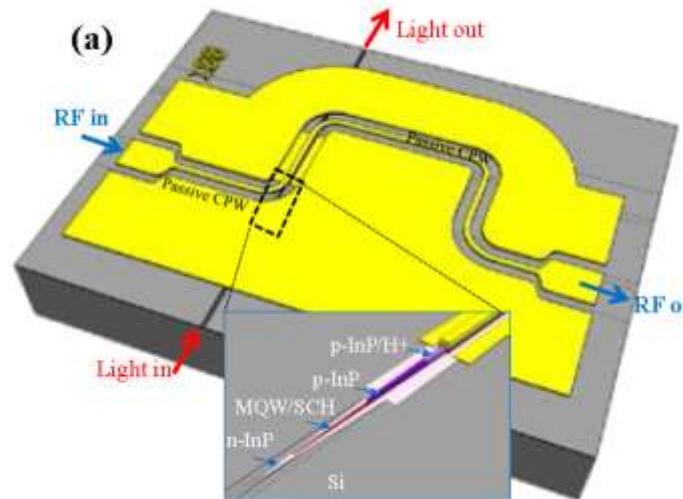
$$\Delta n = \frac{-q^2 \lambda_0^2}{8\pi^2 c^2 n \epsilon_0} \left( \frac{\Delta N_e}{m_{ce}^*} + \frac{\Delta N_h}{m_{ch}^*} \right)$$

$$\Delta \alpha = \frac{q^3 \lambda_0^2}{4\pi^2 c^3 n \epsilon_0} \left( \frac{\Delta N_e}{m_{ce}^{*2} \mu_e} + \frac{\Delta N_h}{m_{ch}^{*2} \mu_h} \right)$$

# Heterogeneous silicon modulators



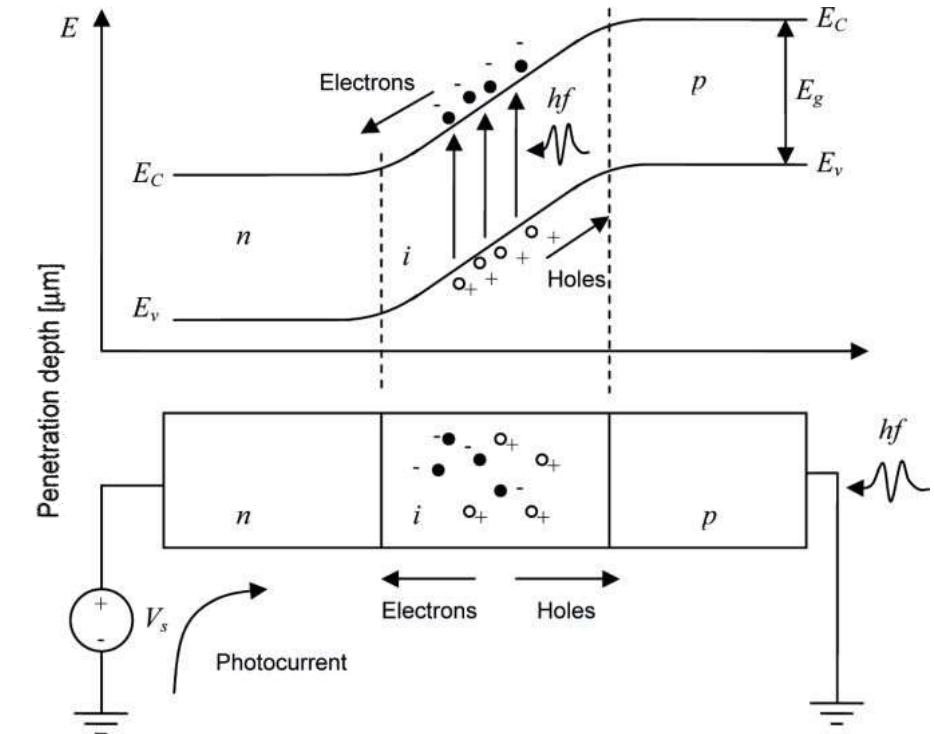
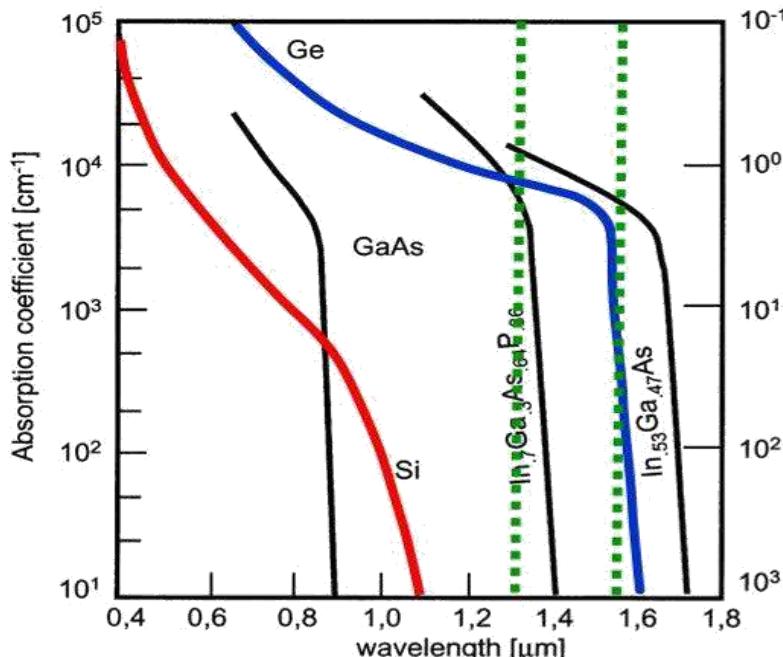
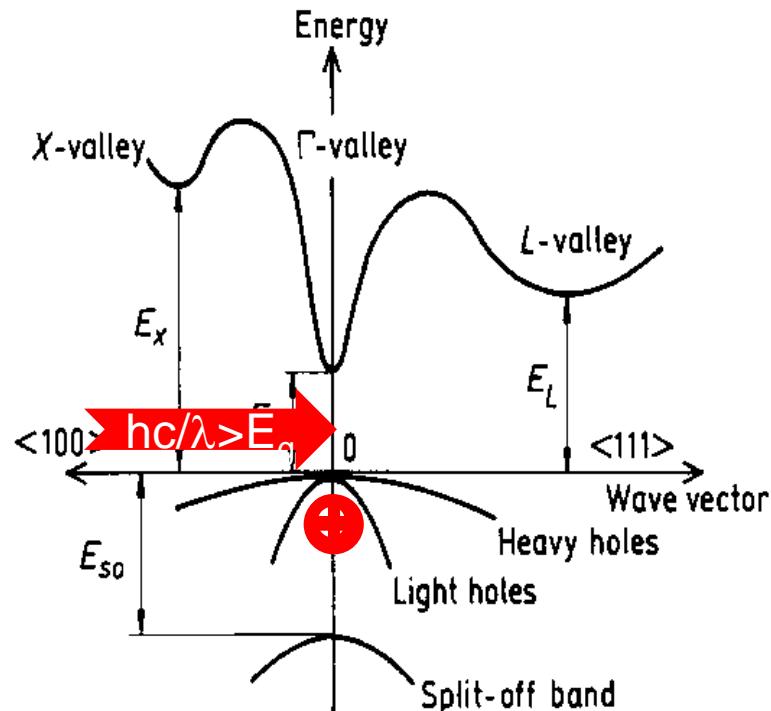
Chen, OE 19, 1455 (2011)



Tang, OE 20, 11529 (2012)

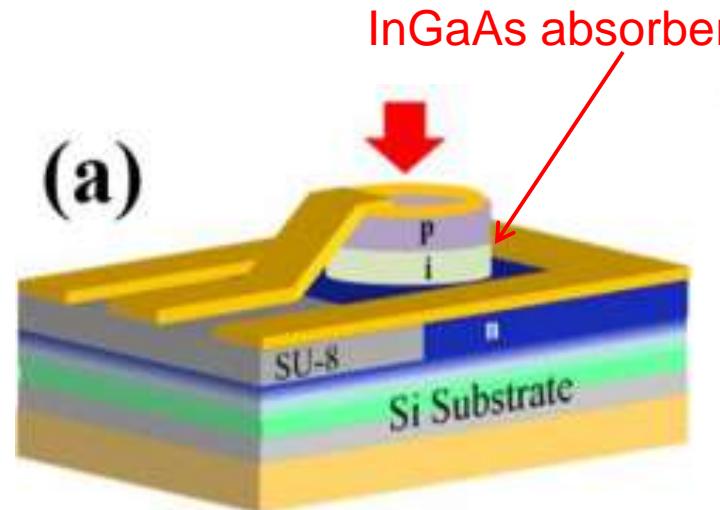
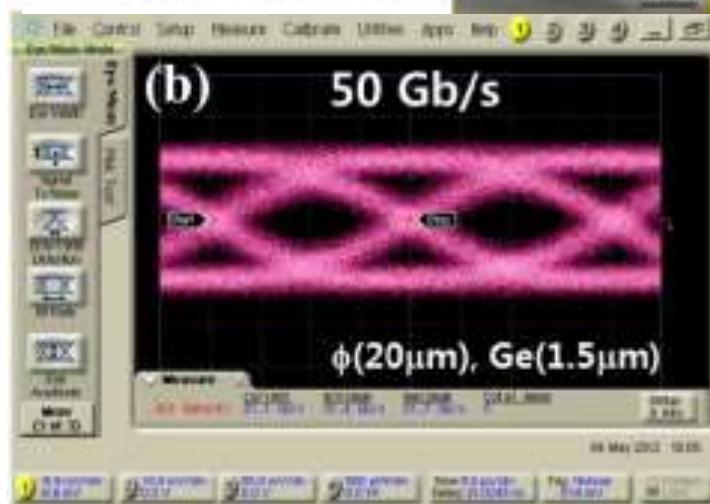
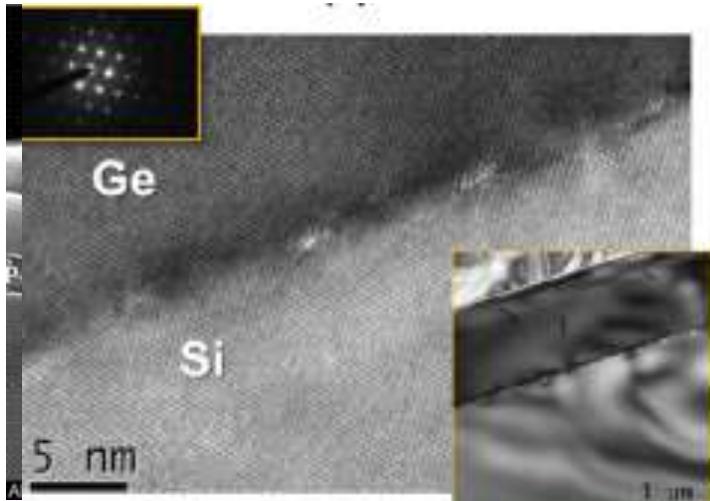
# Photodetection

InGaAs band diagram

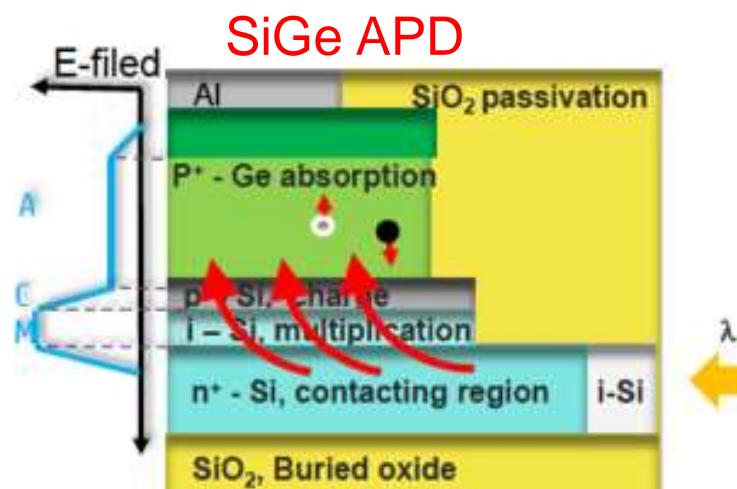


<http://www.ioffe.ru/SVA/NSM/Semicond/GaAs/Figs/421.gif>  
[http://link.springer.com/chapter/10.1007%2F978-1-4419-0304-4\\_6/fulltext.html#Fig6\\_1\\_176711\\_1\\_En](http://link.springer.com/chapter/10.1007%2F978-1-4419-0304-4_6/fulltext.html#Fig6_1_176711_1_En)

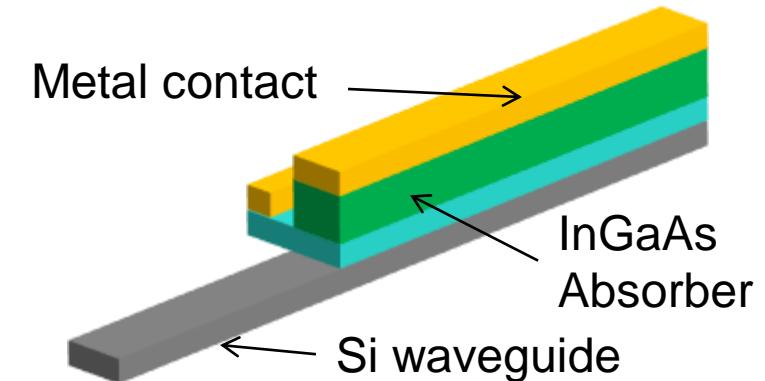
# Silicon-based photodetectors



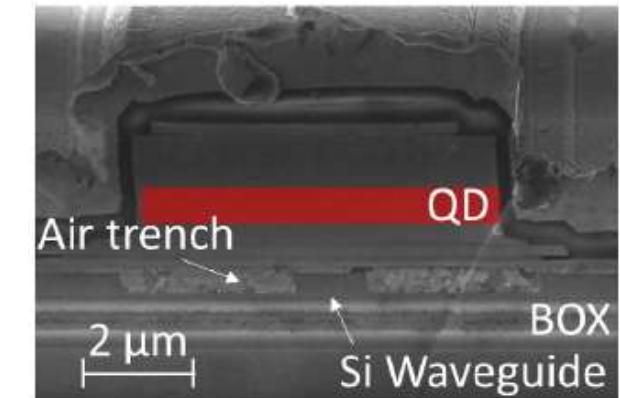
Sun, OE 26, 13605 (2018)



Huang, Optica 3, 793 (2016)



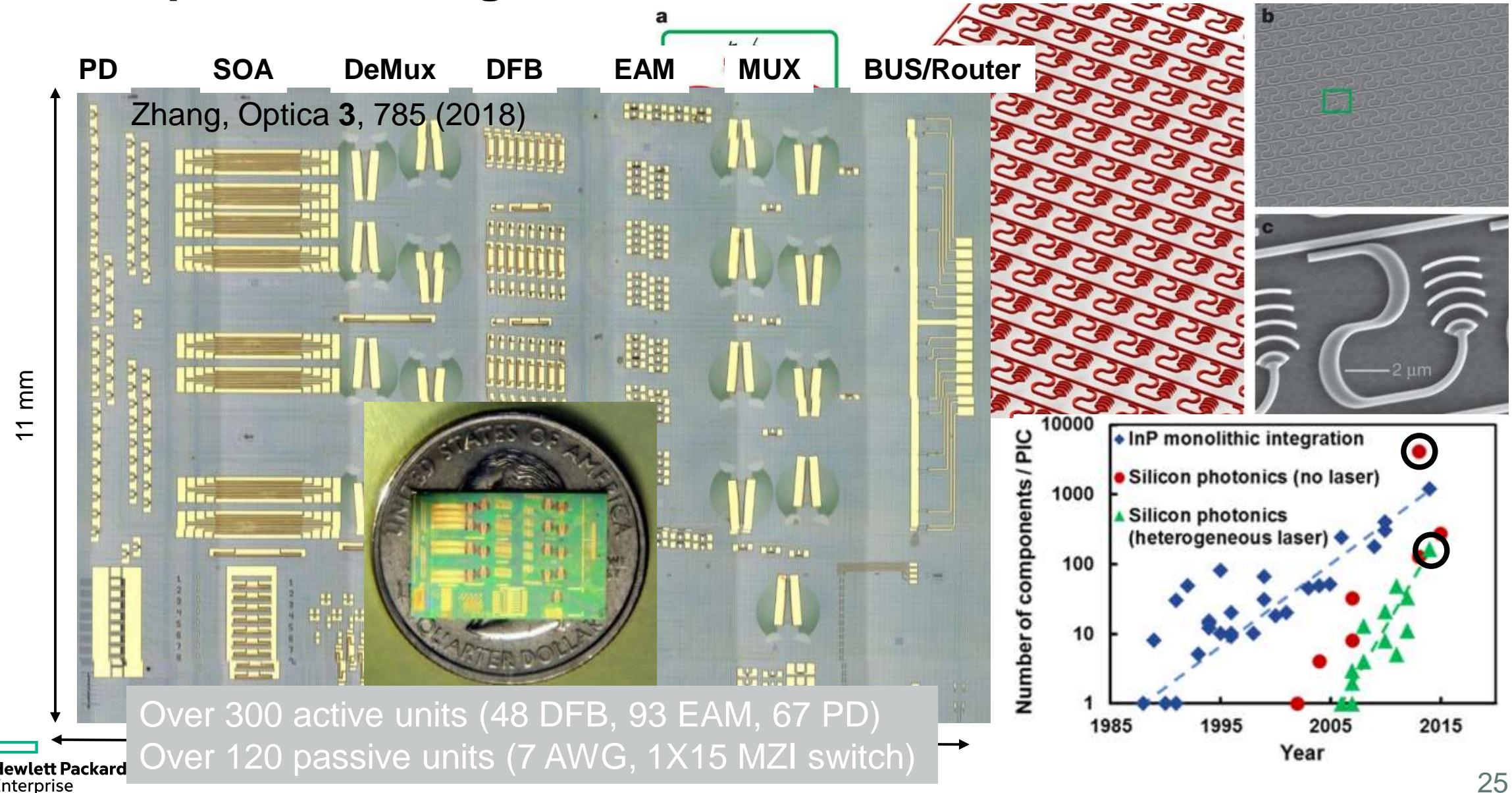
Kurczveil, OI (2016)



Tossoun, DRC (2018)

# Silicon photonic integration

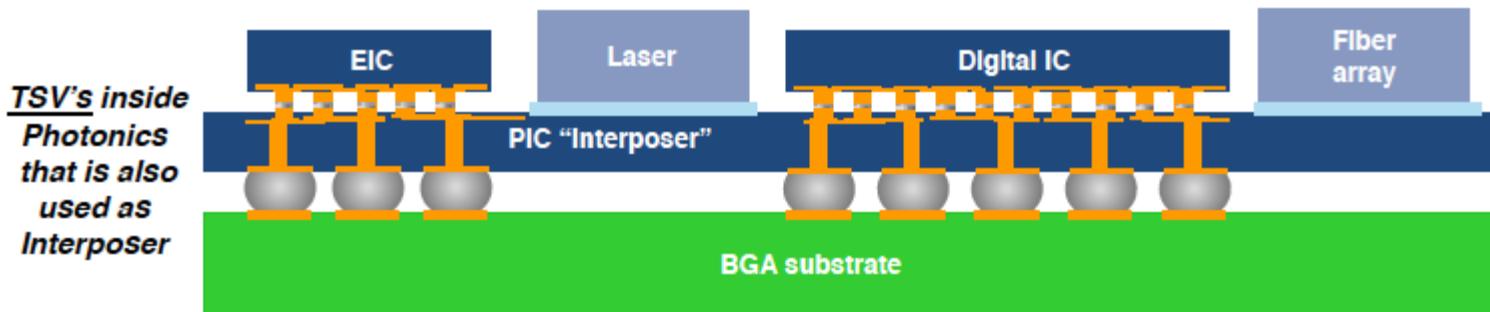
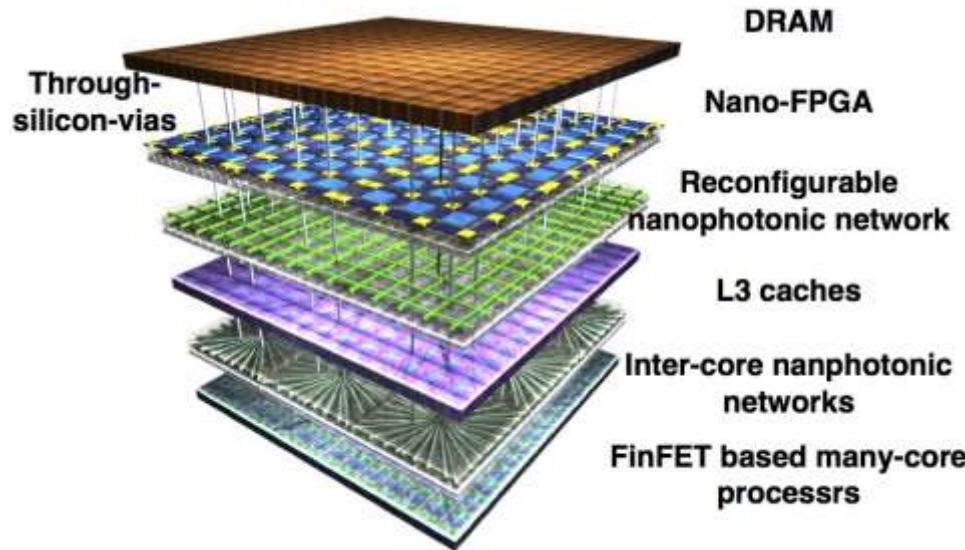
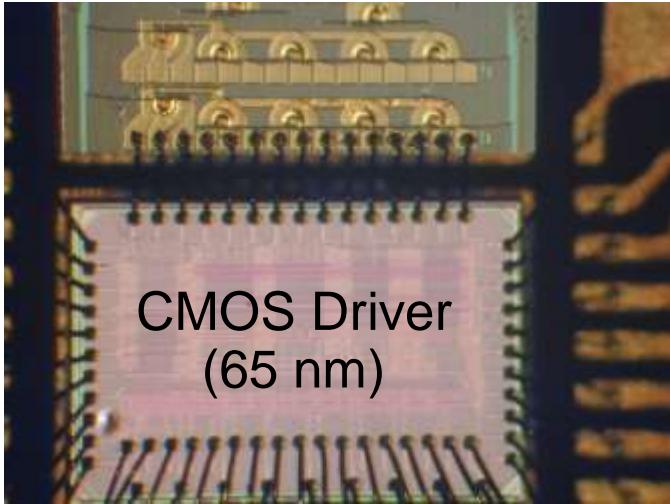
Sun, Nature 439, 195 (2013)



# Silicon photonics - electronics hybrid integration

## 2D, 2.5D and 3D integration schemes

### Optical Transmitter



EIC & DIGITAL IC assembled with  $\mu$ -Copper pillars an active PIC "Interposer"



### -2D integration

- Simple, mature
- Limited bandwidth

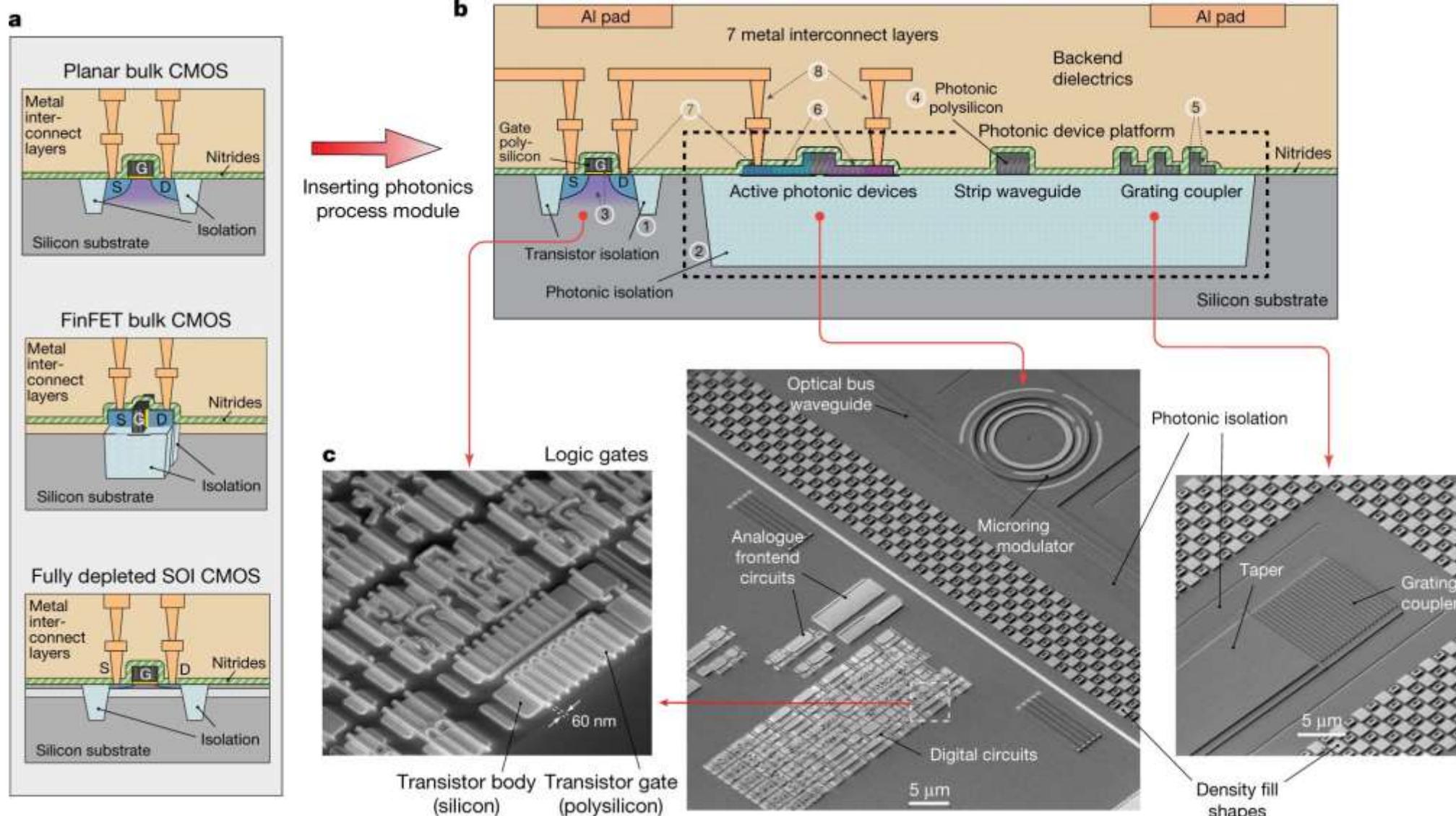
### -2.5D integration

- High speed, low power consumption
- Fabrication, thermal management

### -3D integration

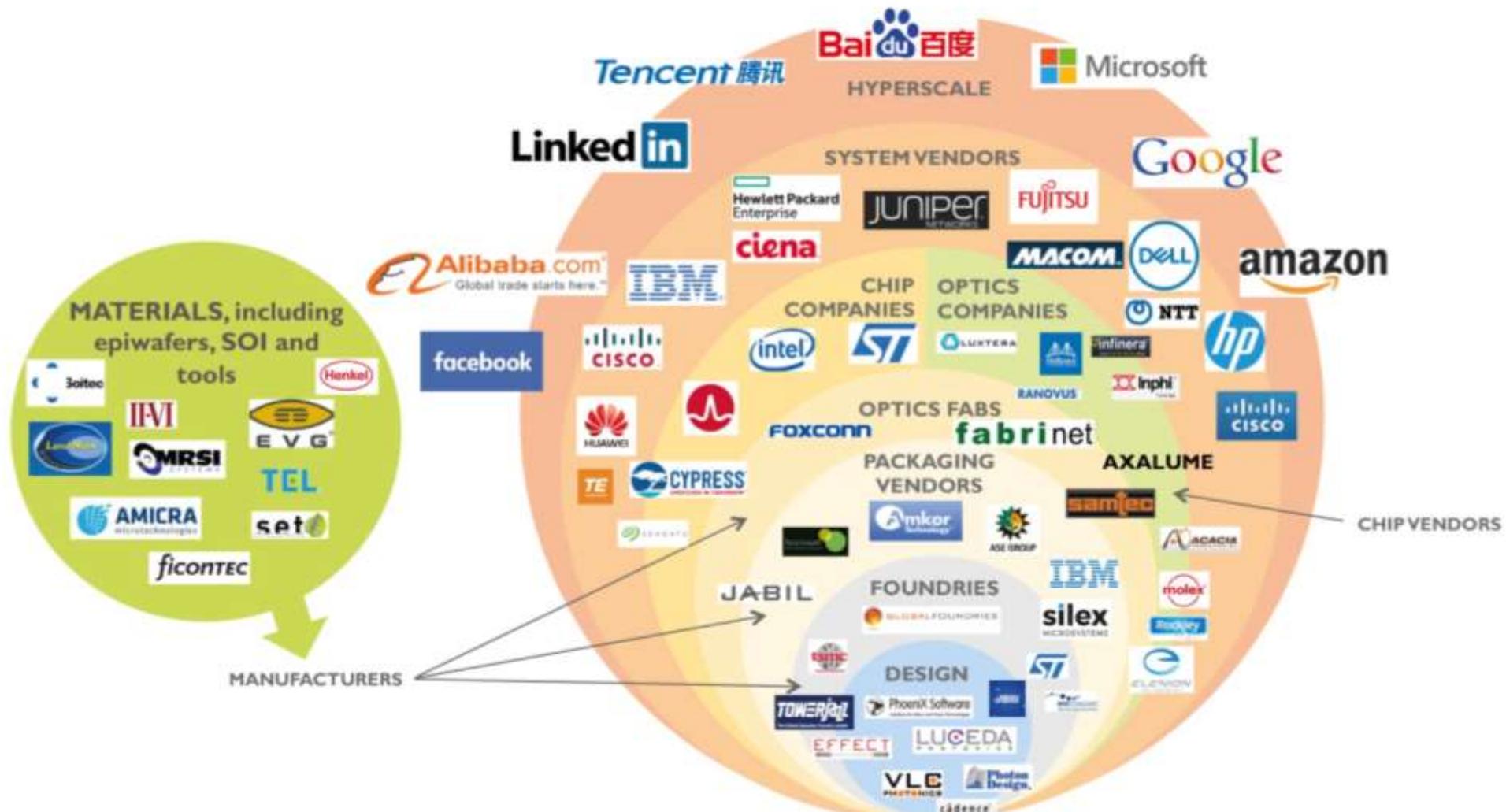
- Largest bandwidth, smallest footprint
- Thermal management, system design, reliability

# Silicon photonics - electronics monolithic integration



# Si Photonics: ecosystems & stakeholders in 2017

(Source: Silicon Photonics 2018 report, Yole Développement, January 2018)



---

# Summary

- Key factors in photonic integration: functionality, material and fabrication compatibility
- Silicon photonic building blocks getting mature and complete in past 15 years
- On-chip laser: still primary R&D component and reliability determining factor
- Photonics – electronics integration: a challenging balance of bandwidth – thermal management – cost
- Silicon photonic ecosystem: vertical integration presently; open and horizontal integration necessary
  
- Helps needed from EDA community
  - Advanced active photonic component simulation (Optical, electrical, thermal)
  - Packaged module level simulation (Optical, electrical, thermal, mechanical)
  - Reliability simulation of III-V and Ge components on silicon and integrated chips